

Fig. 1A

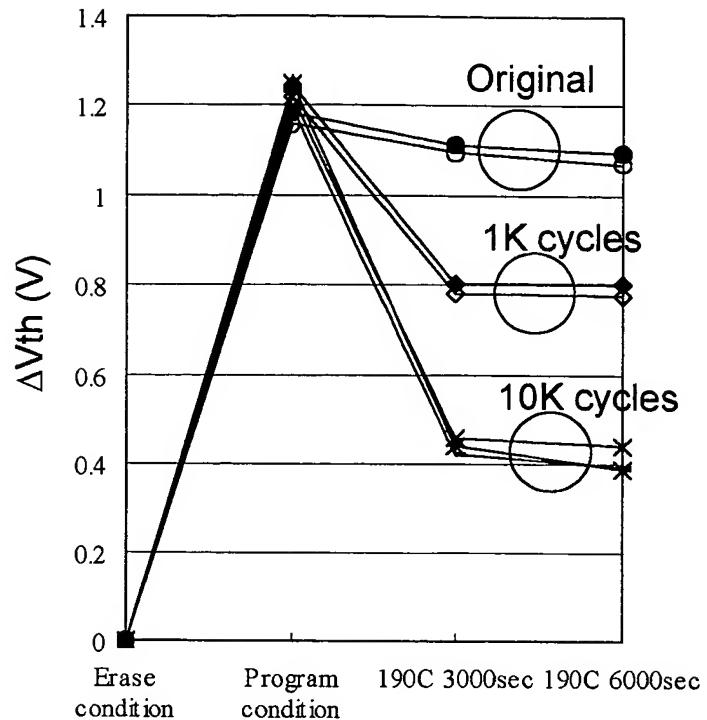


Fig. 1

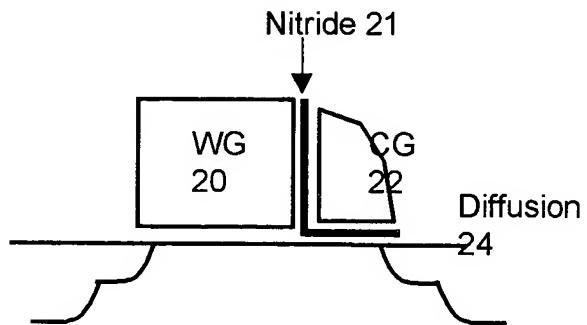


Fig.2

Prior Art

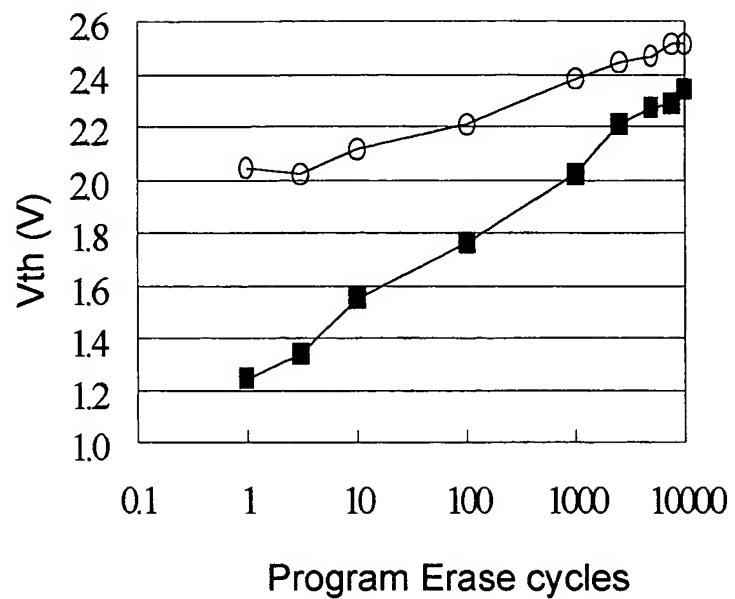


Fig.3

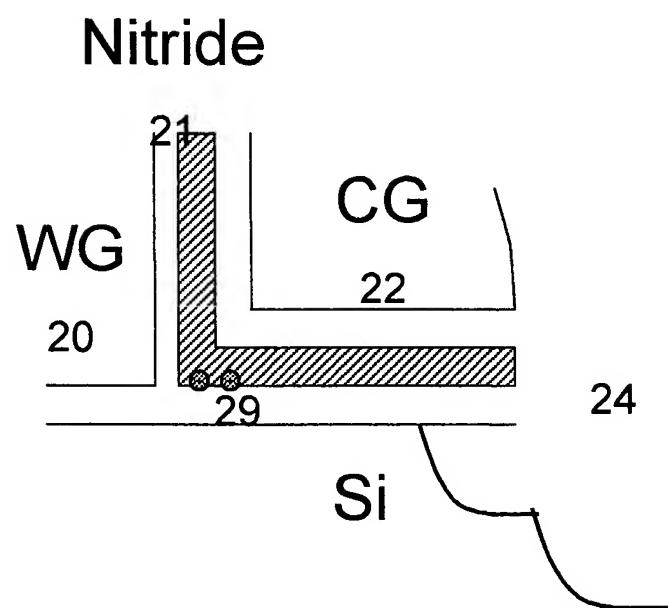


Fig.4

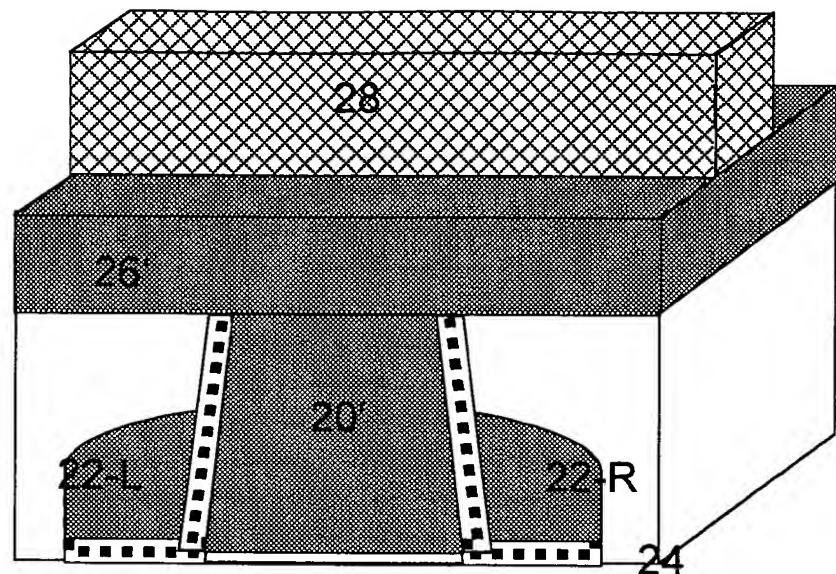


Fig.5A

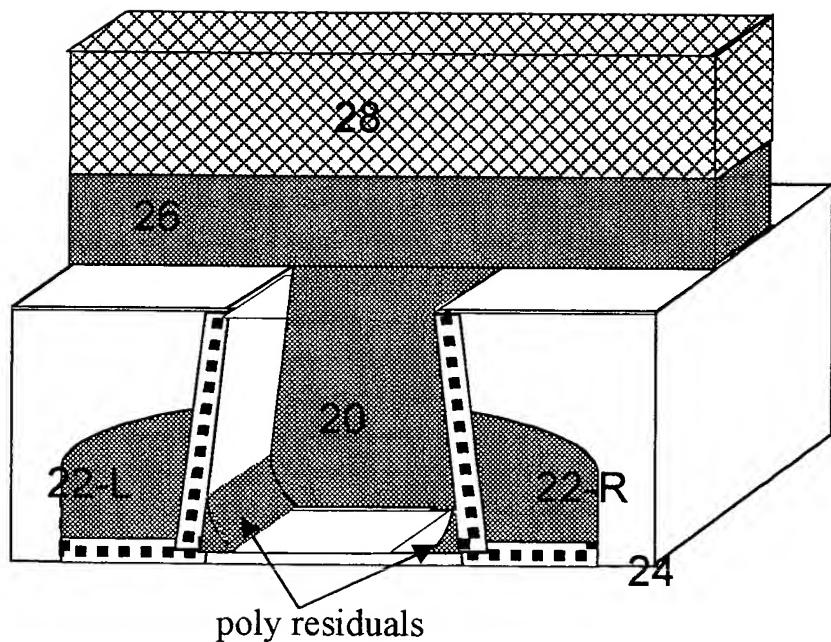


Fig.5B

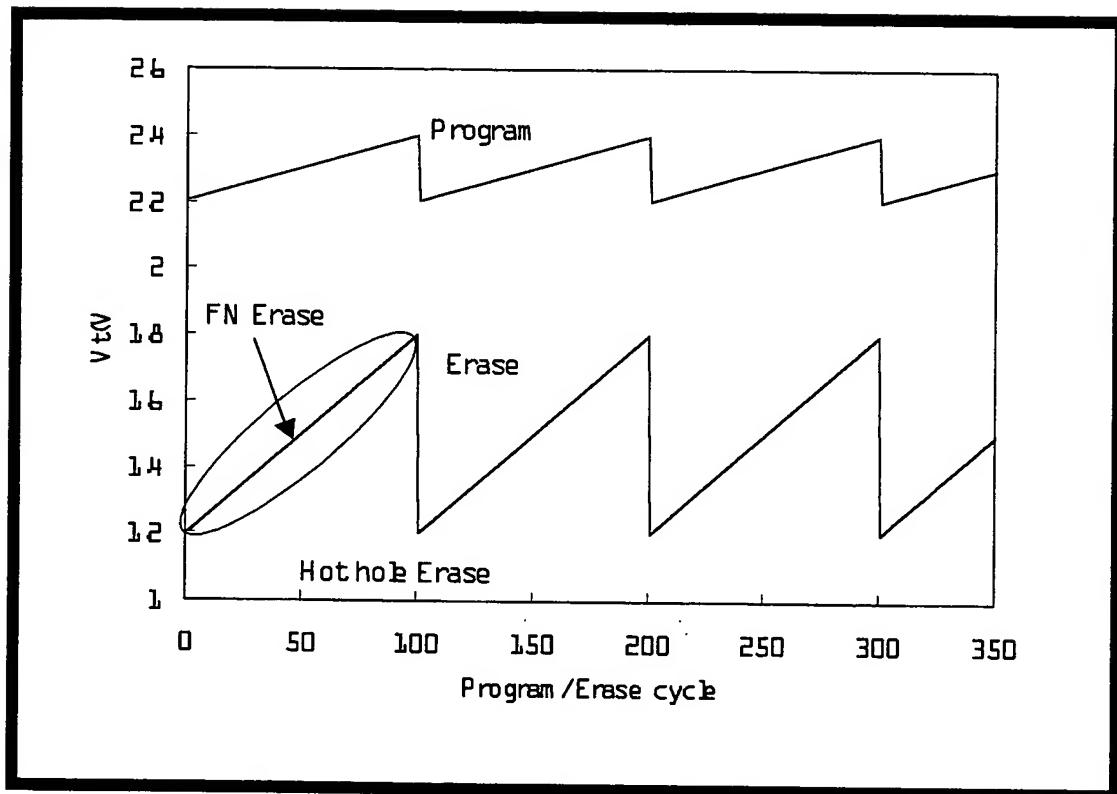


Fig.6

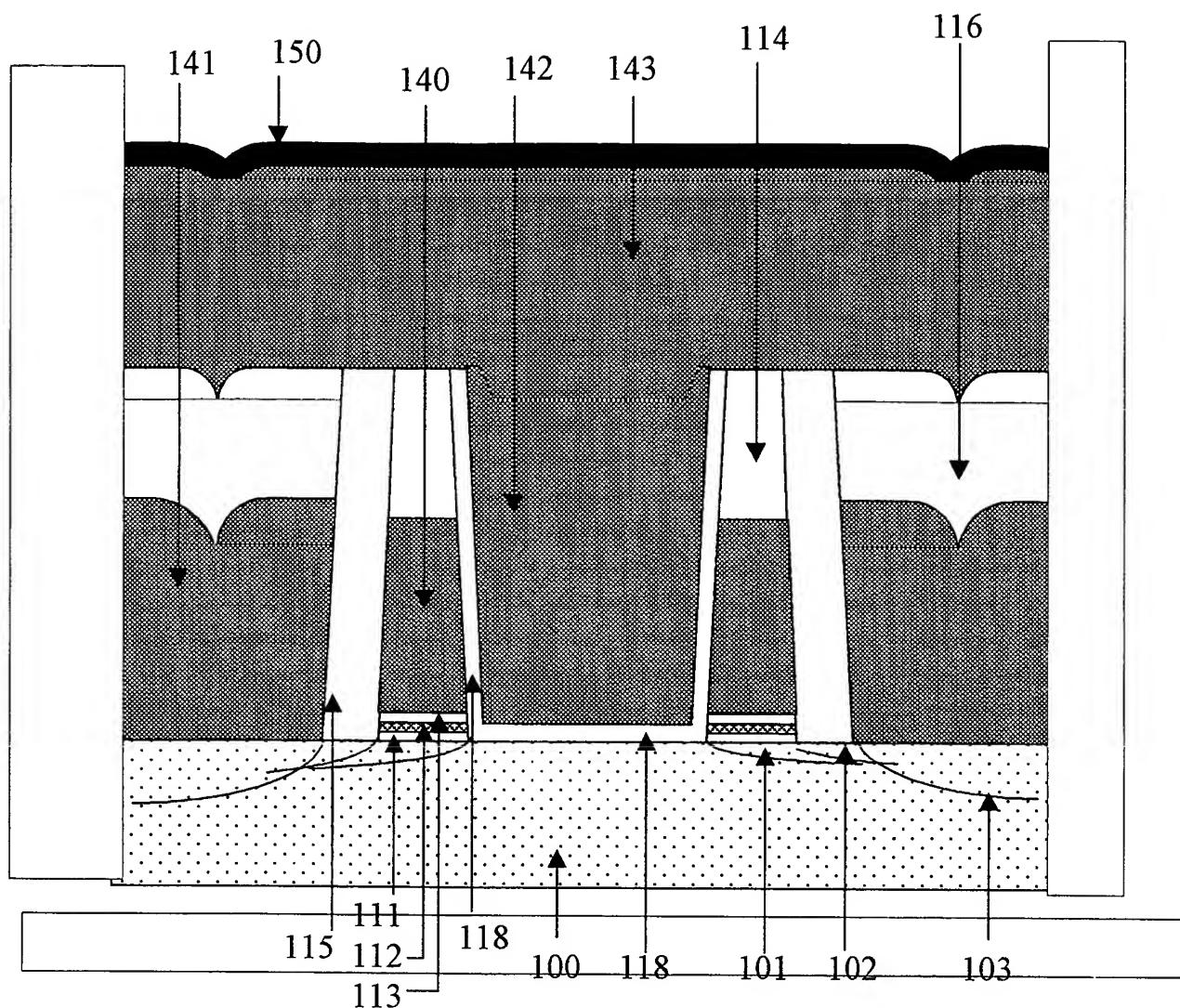


Fig.7

100 Substrate	111 ONO Bottom oxide	140 Control Gate Poly Si
101 Control Gate Channel	112 ONO Nitride	141 Raised Diffusion Poly Si
102 Memory LDD	113 ONO Top oxide	142 Word gate
103 Memory diffusion	114 CG Oxide Mask	143 Word Line
	115 Memory Spacer	150 Word Line Salicide
	116 Recess Oxide	
	117 CG-WG isolation	
	118 Word Gate Oxide	

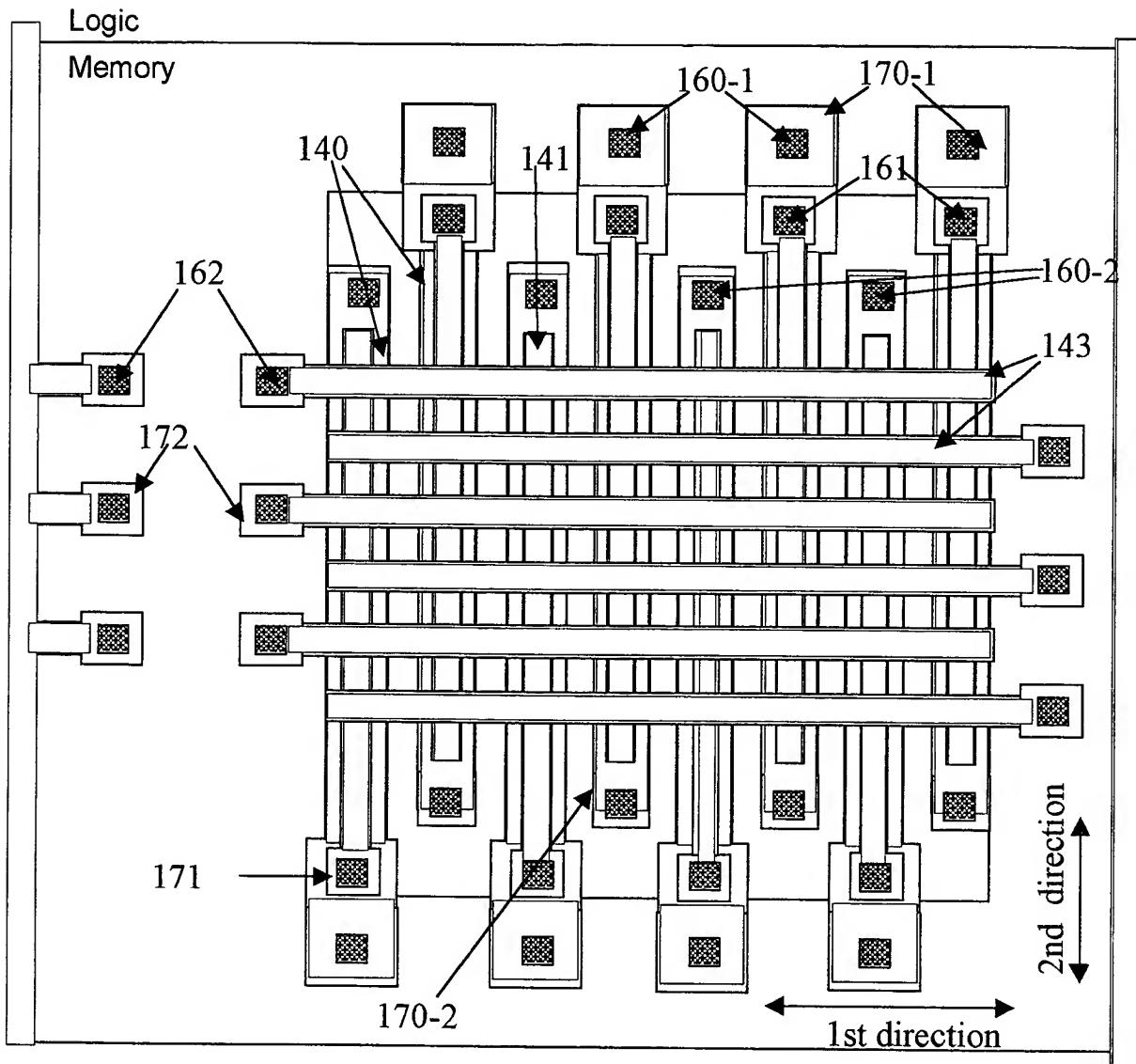


Fig.8

160-1Control Gate Contact type 1
 160-2Control Gate Contact type 2
 161 Bit line (Diffusion) Contact
 162 Word line Contact

170-1Control Gate Contact type 1 Cover
 170-2Control Gate Contact type 2 Cover
 171 Bit line (Diffusion) Contact Cover
 172 Word line Contact Cover

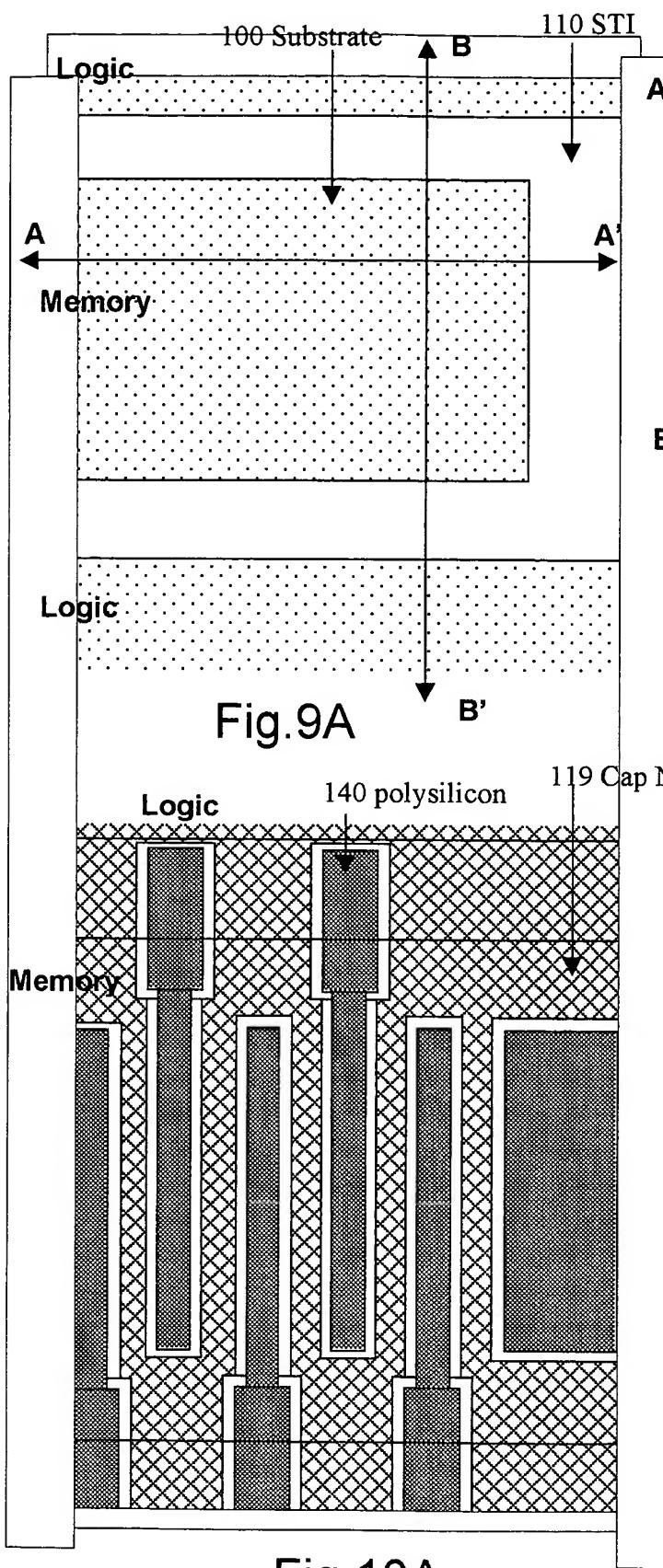


Fig.10A

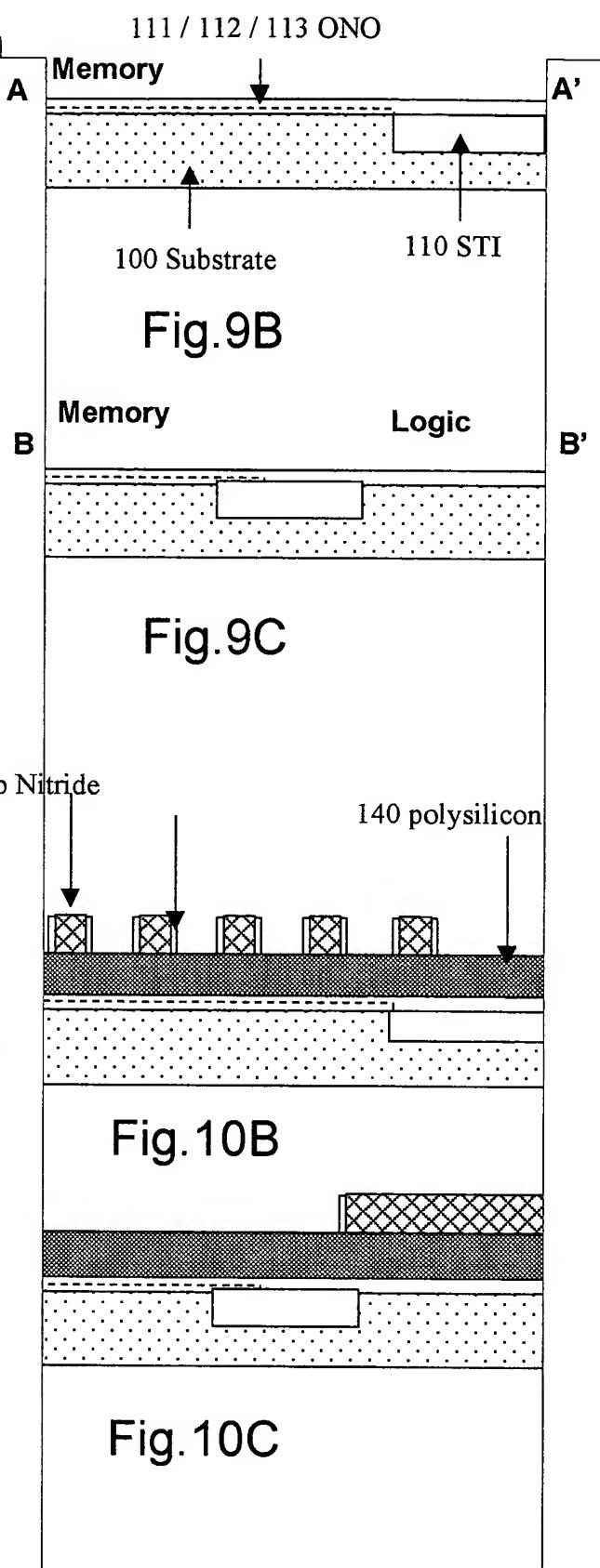
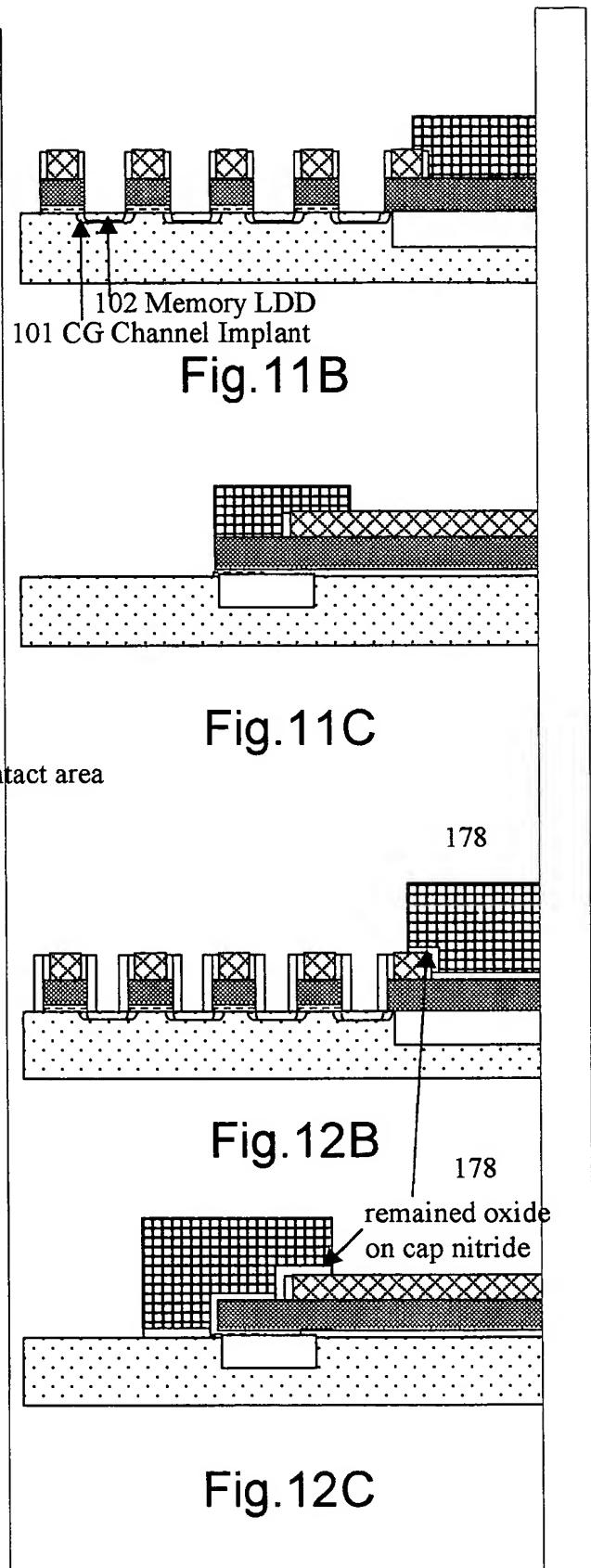
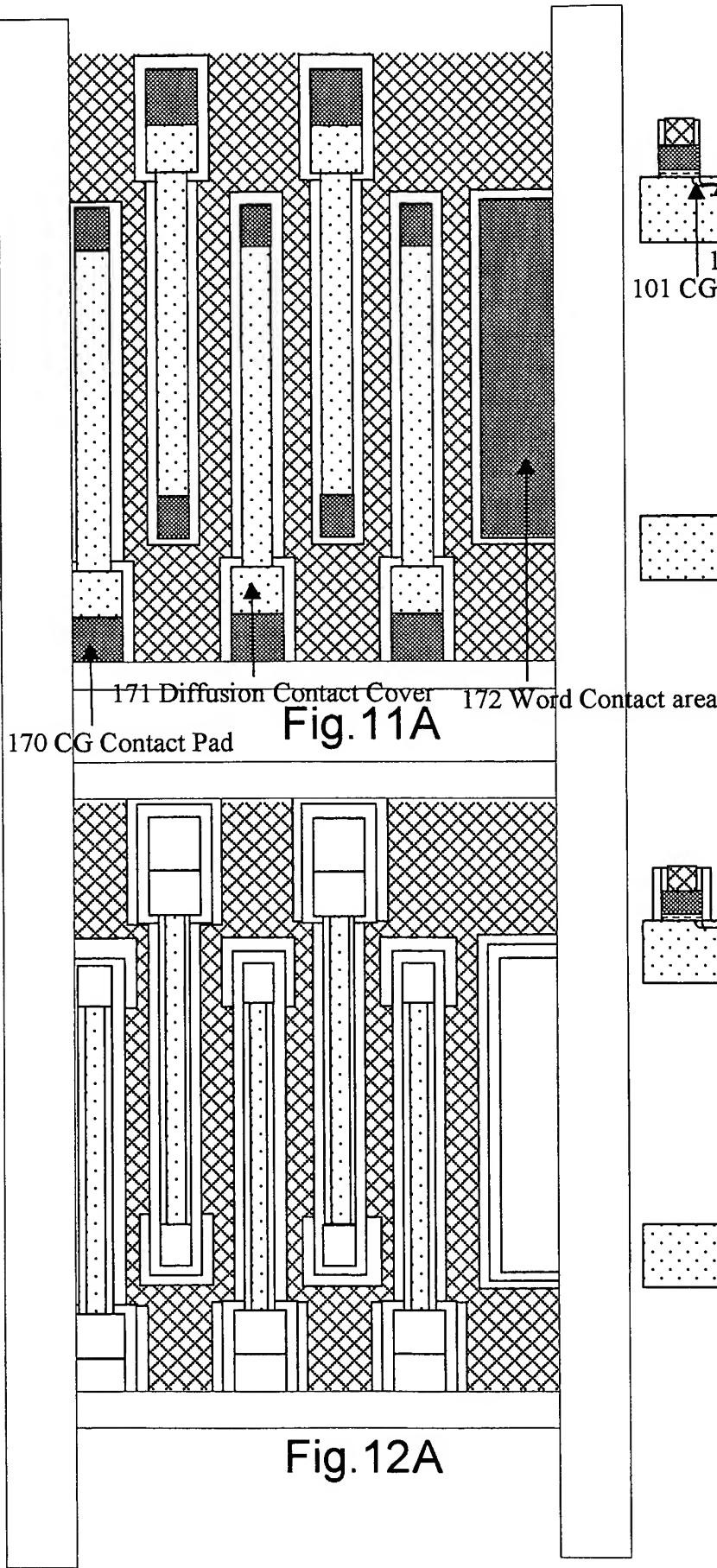
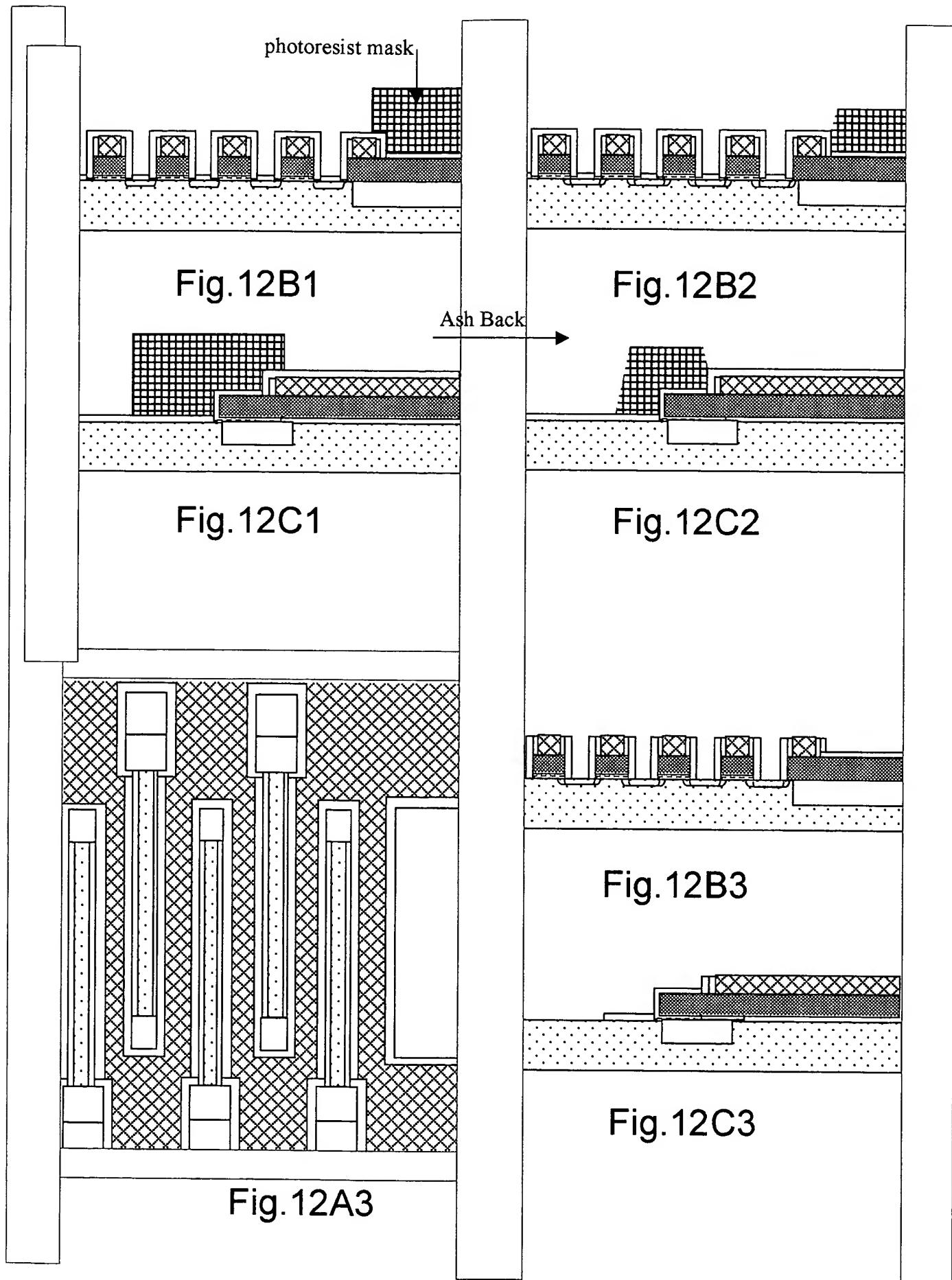


Fig.10C





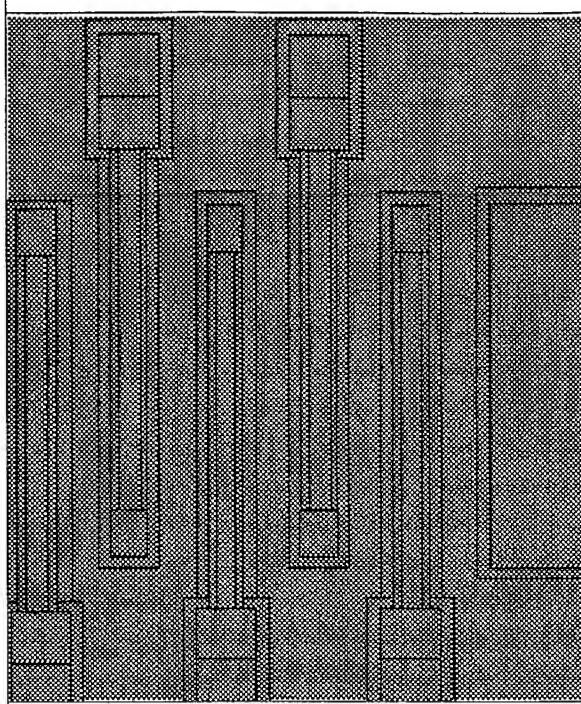


Fig.13A

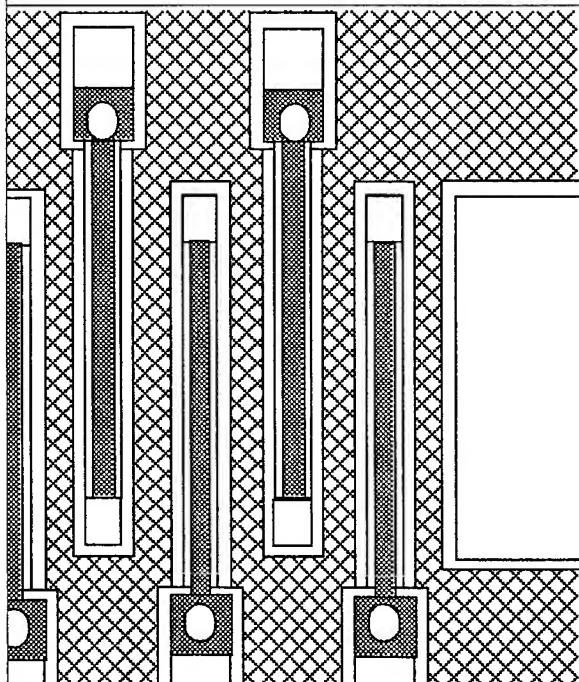
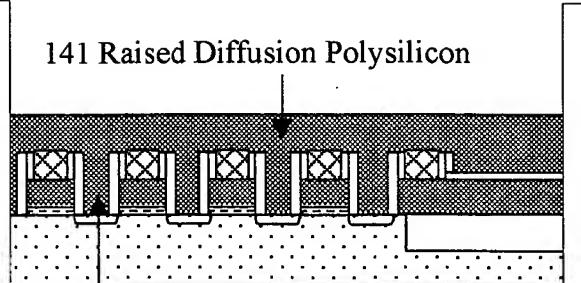


Fig.14A



180 Diffusion Trench

Fig.13B

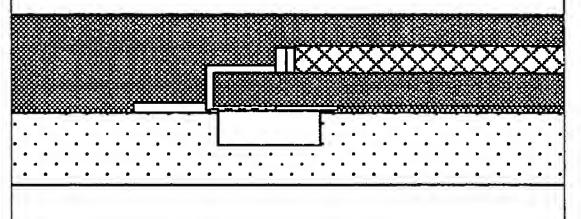


Fig.13C

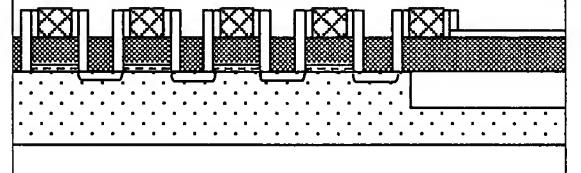


Fig.14B

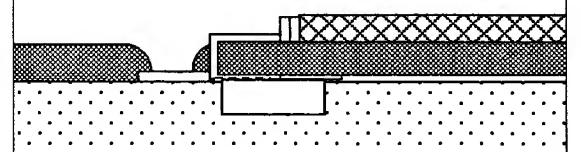


Fig.14C

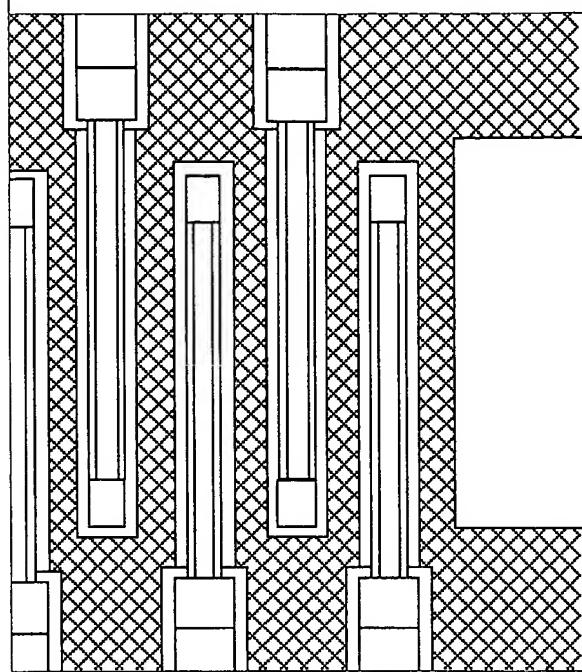


Fig.15A

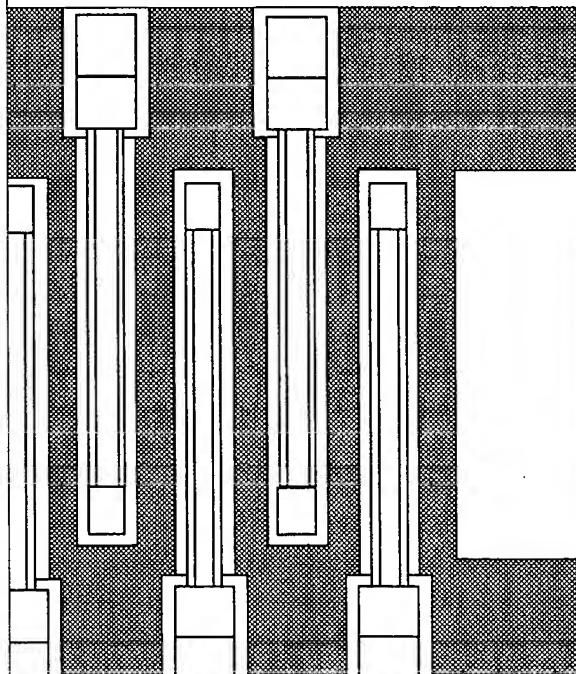


Fig.16A

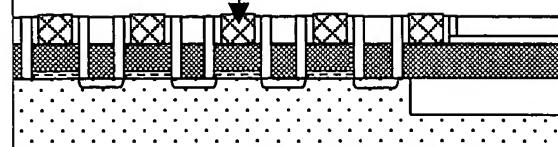


Fig.15B

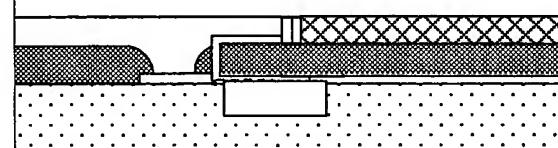


Fig.15C

142 Word Gate Trench

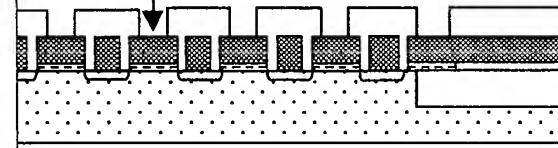


Fig.16B

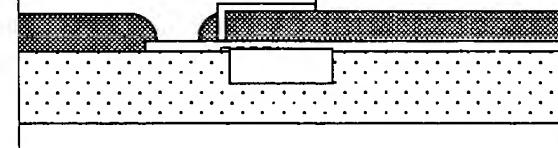
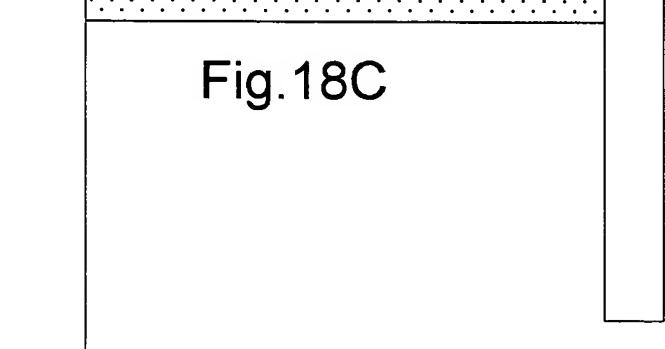
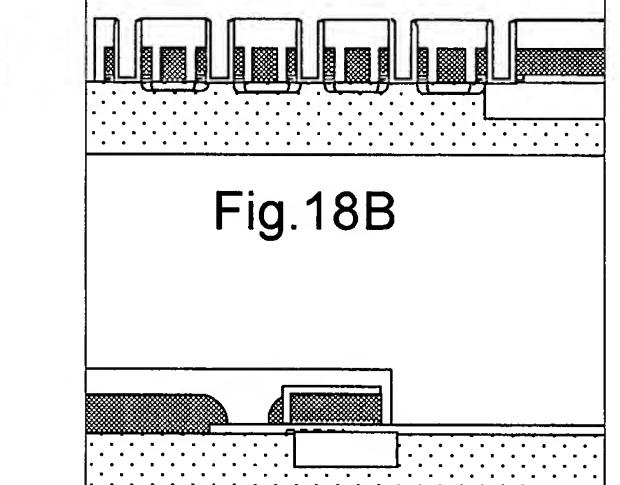
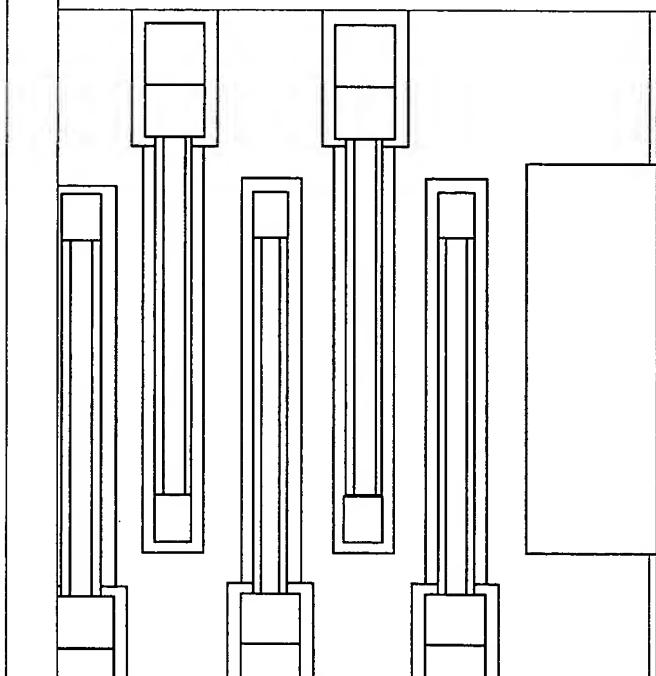
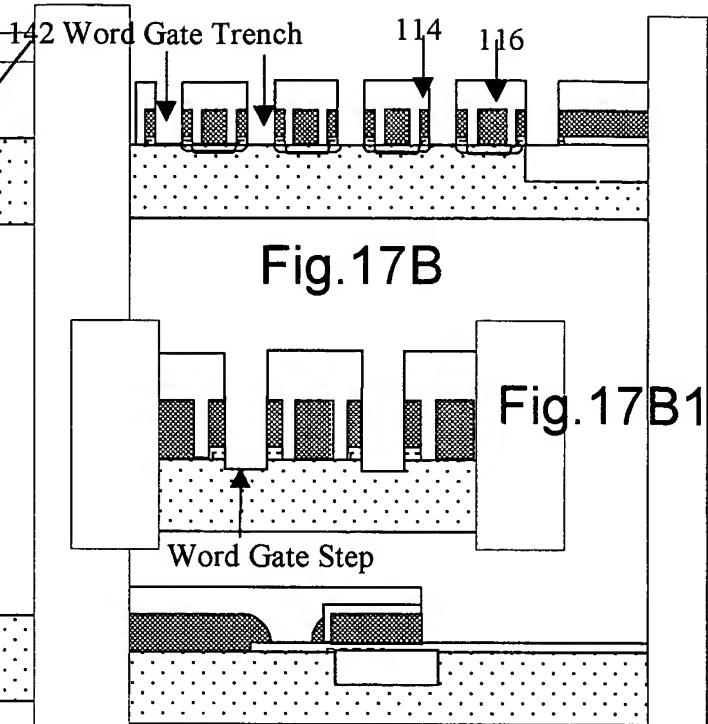
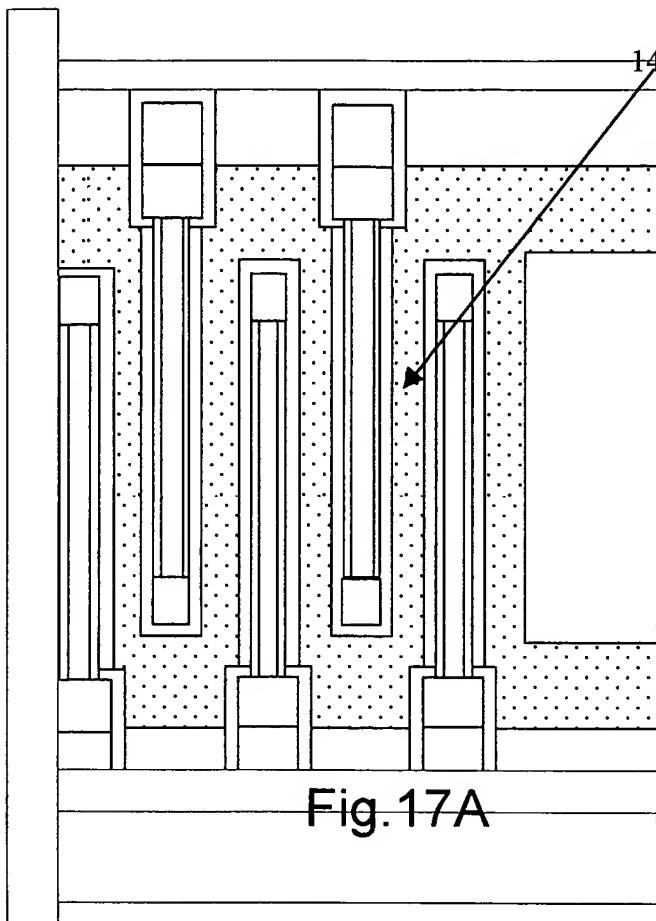


Fig.16C



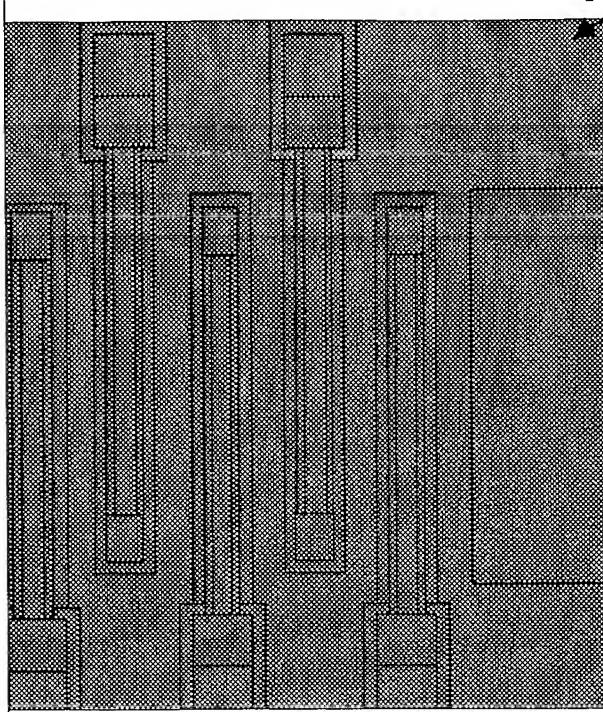
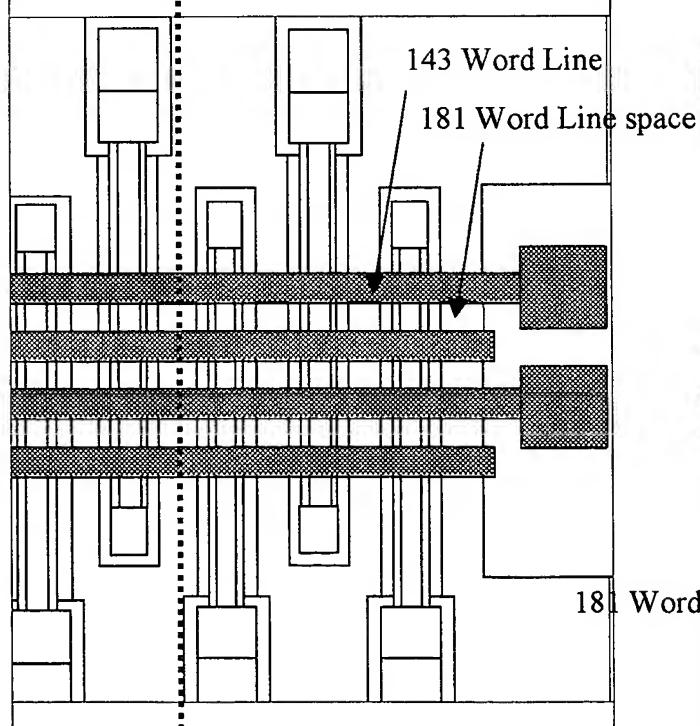


Fig.19A

C



C'

Fig.20A

143 Word Line polysilicon

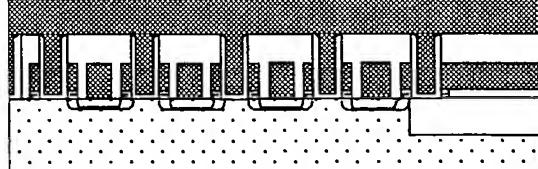


Fig.19B

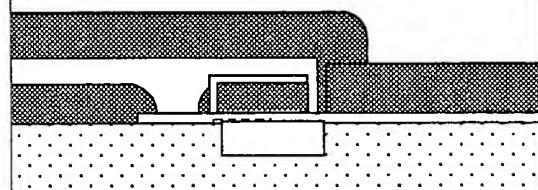


Fig.19C

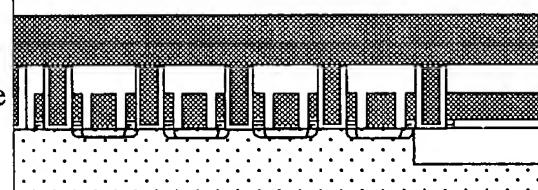
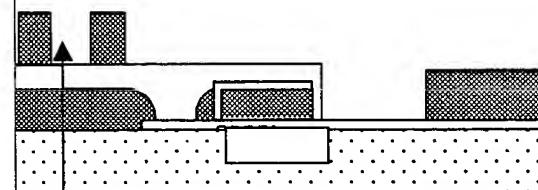


Fig.20B



181 Word Line space Fig.20C

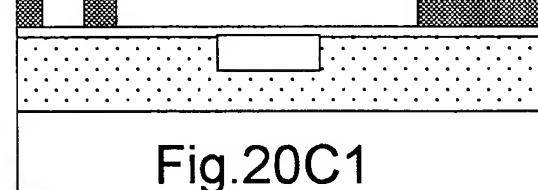


Fig.20C1

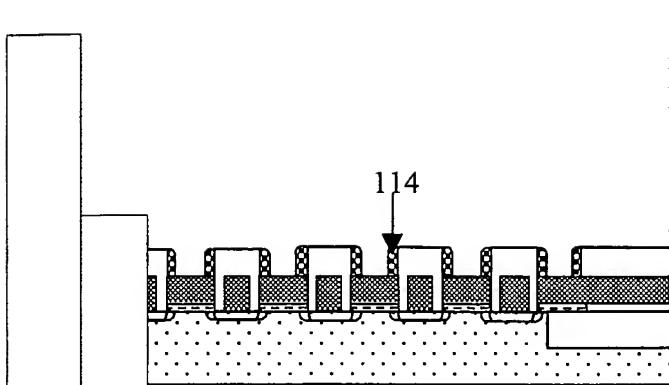


Fig.21B

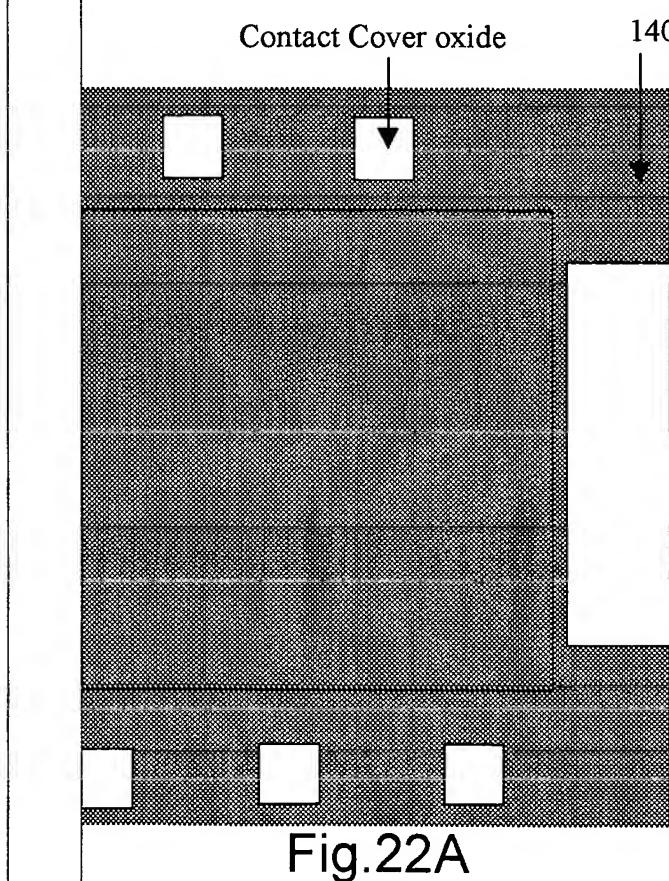


Fig.22A

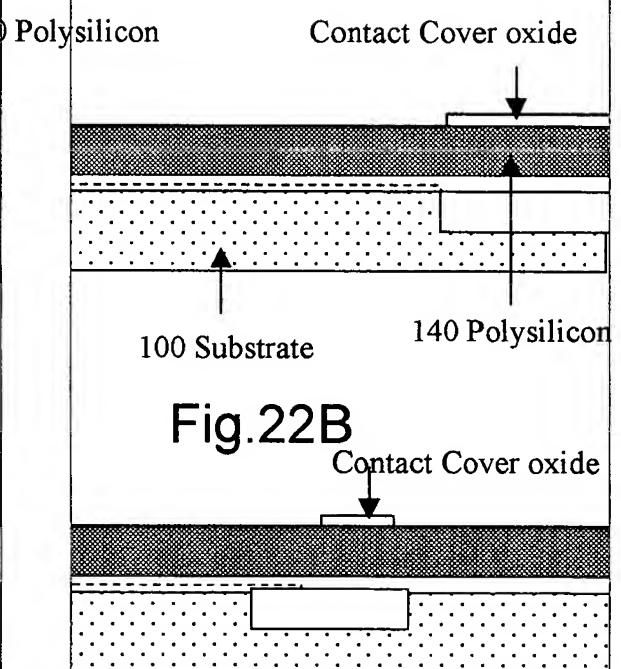


Fig.22B

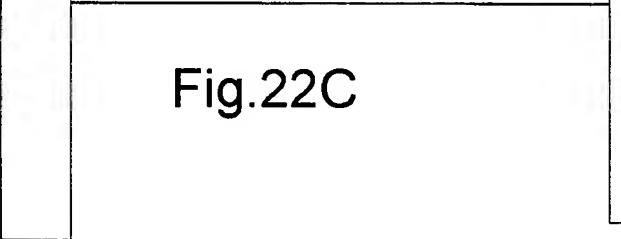


Fig.22C

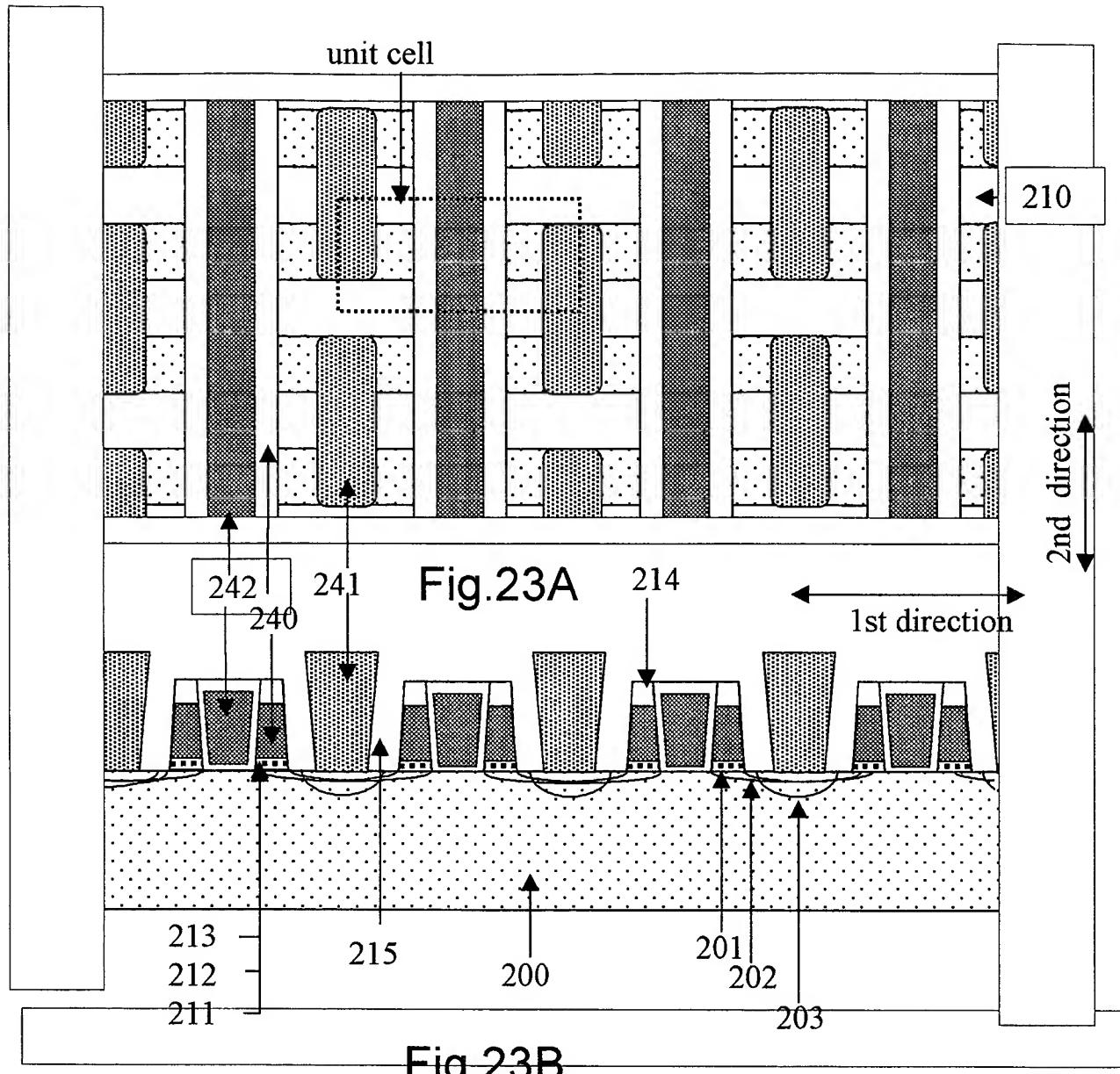
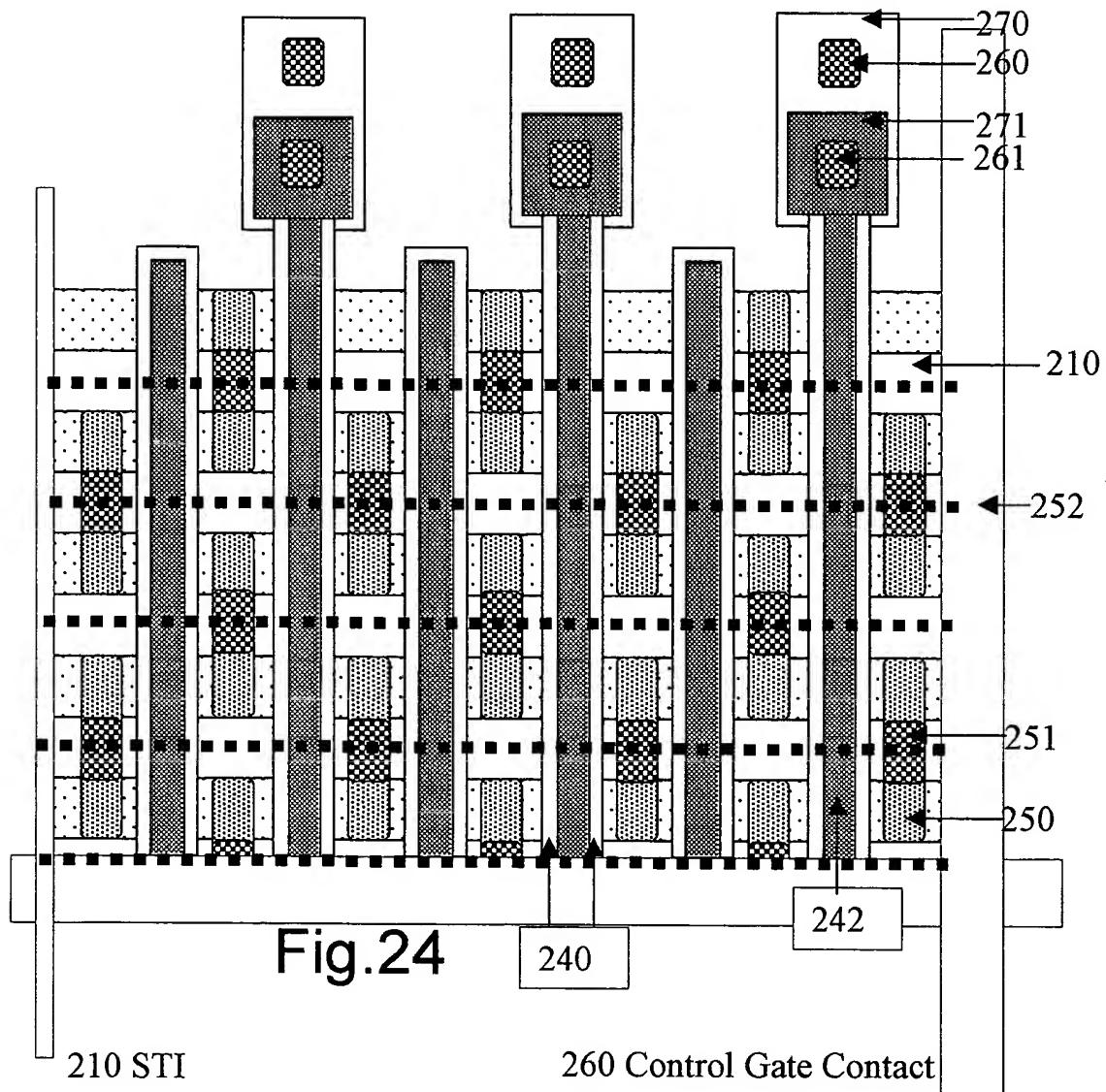


Fig.23B

200 Substrate	211 ONO Bottom oxide	240 Control Gate Poly Si
201 Control Gate Channel	212 ONO Nitride	241 Local wiring
202 Memory LDD	213 ONO Top oxide	242 Word gate/Line
203 Memory diffusion	214 CG Oxide Mask	
	215 Memory Spacer	
	216 CG-WG isolation	
	217 Word Gate Oxide	
	218 Word cap oxide	



210 STI

240 Control Gate

242 Word Line

250 Local Wire (bit bridge)

251 Bit line Contact

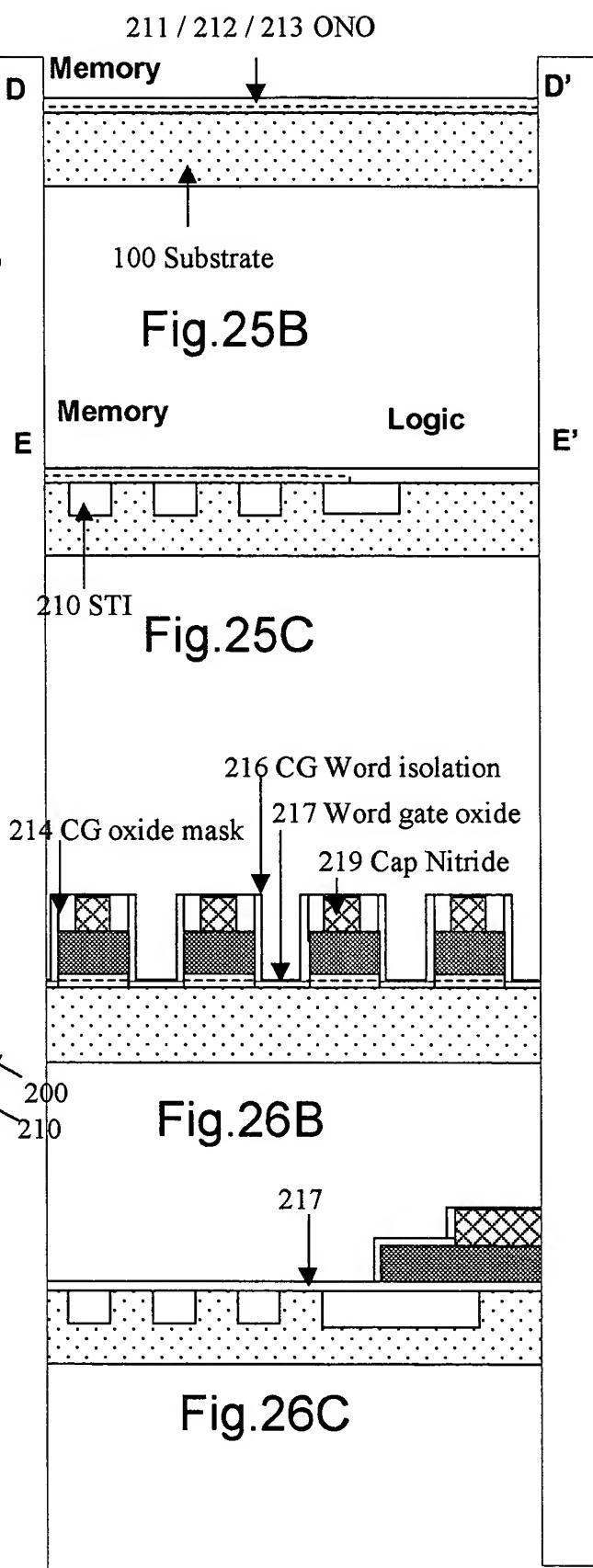
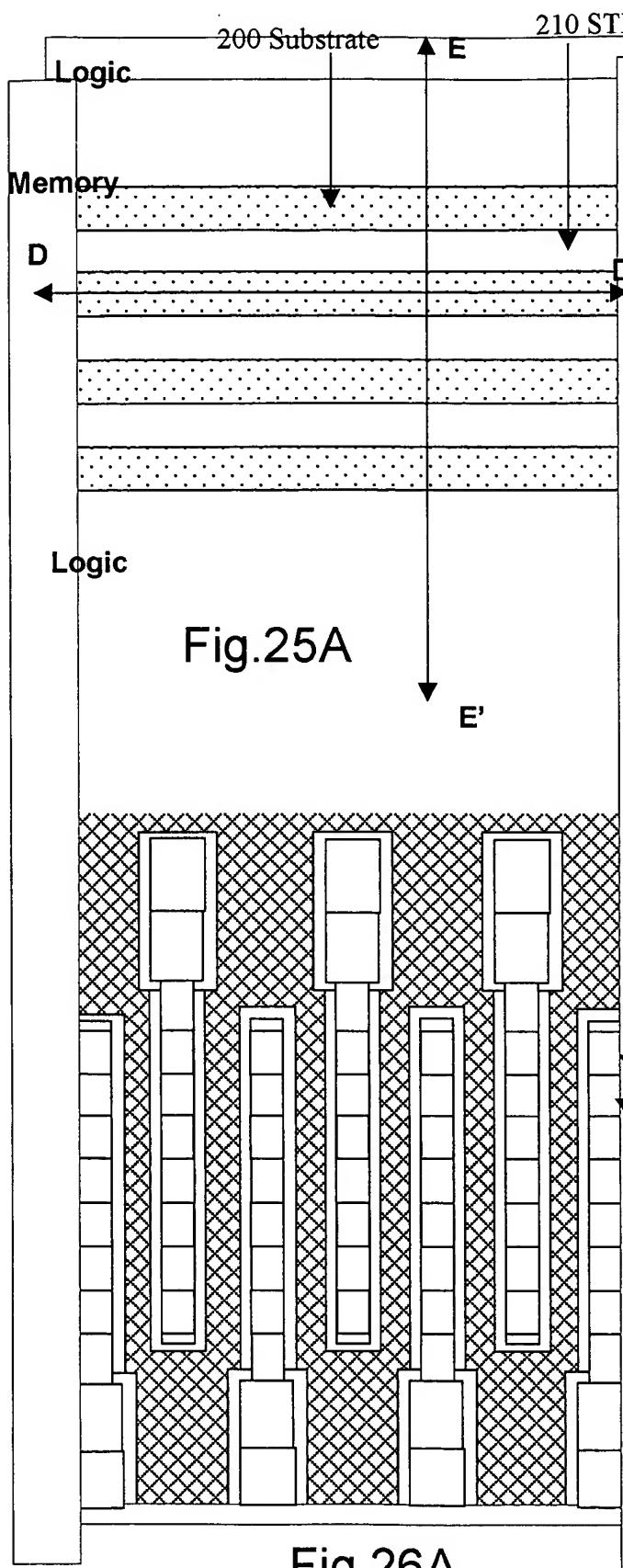
252 Bit Line (1st Metal)

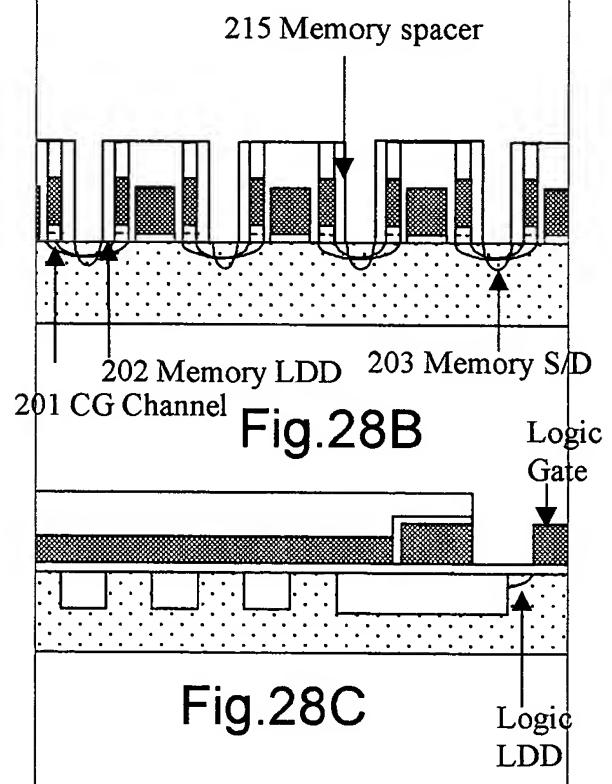
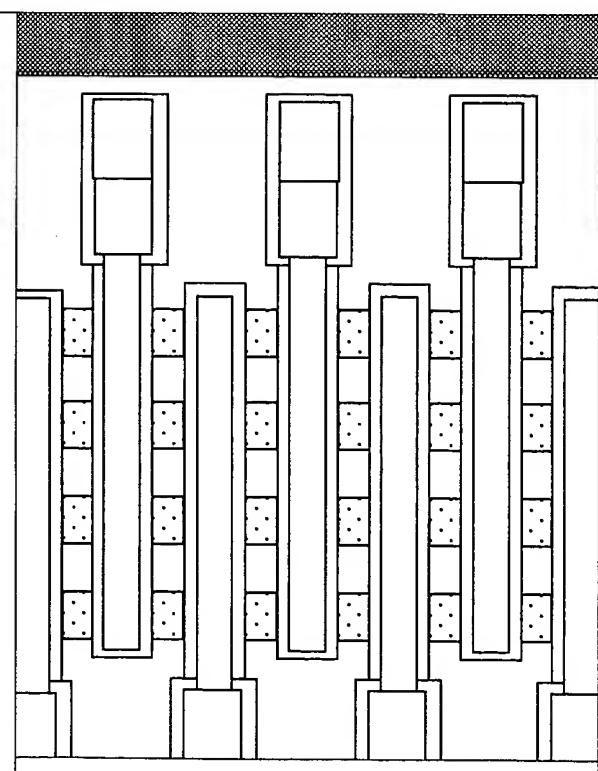
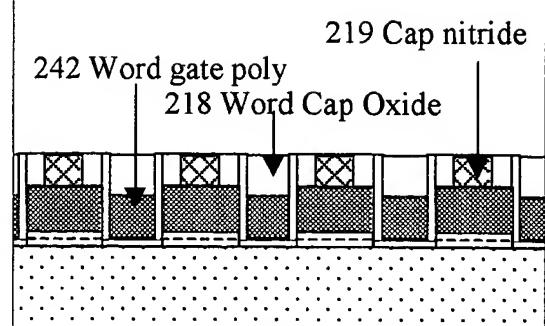
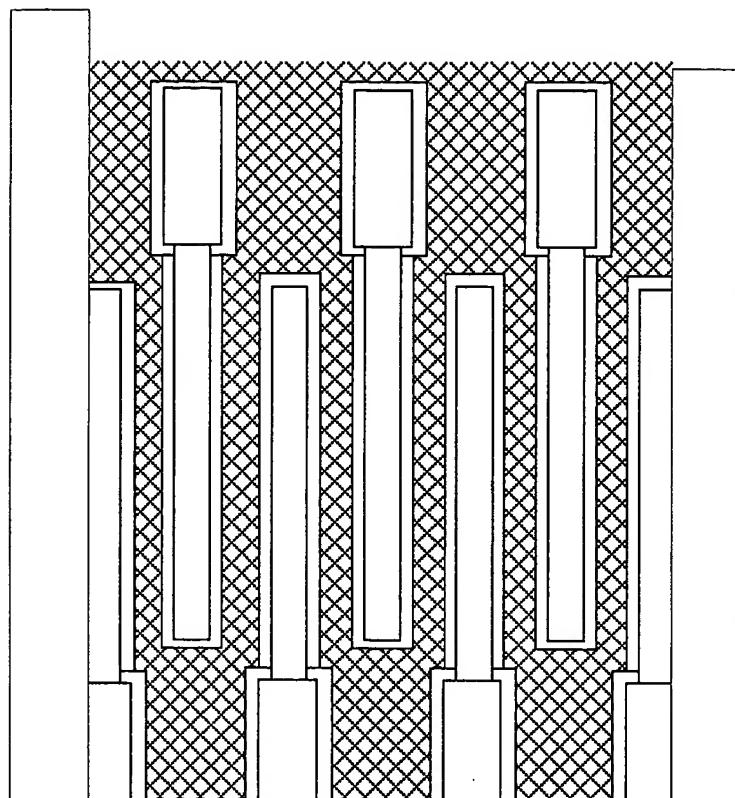
260 Control Gate Contact

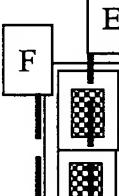
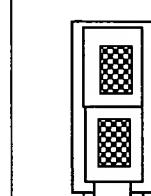
261 Word Line Contact

270 Control Gate Contact Cover

271 Word line Contact Cover







E

F

E'

F'

Fig.29A

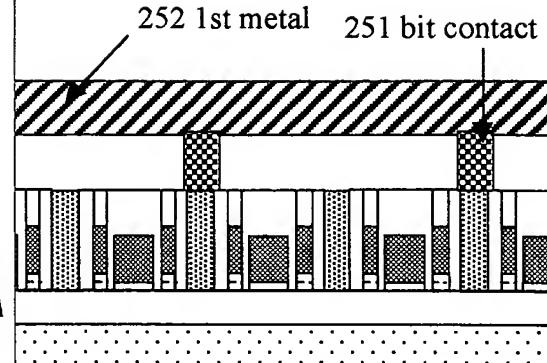


Fig.29B

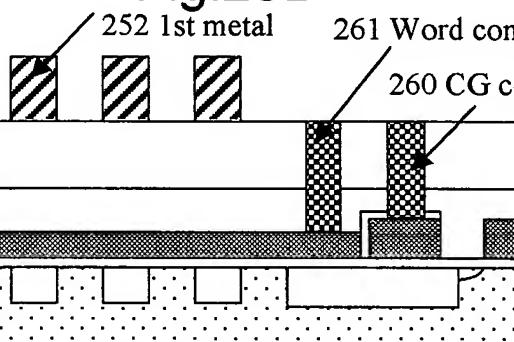


Fig.29C

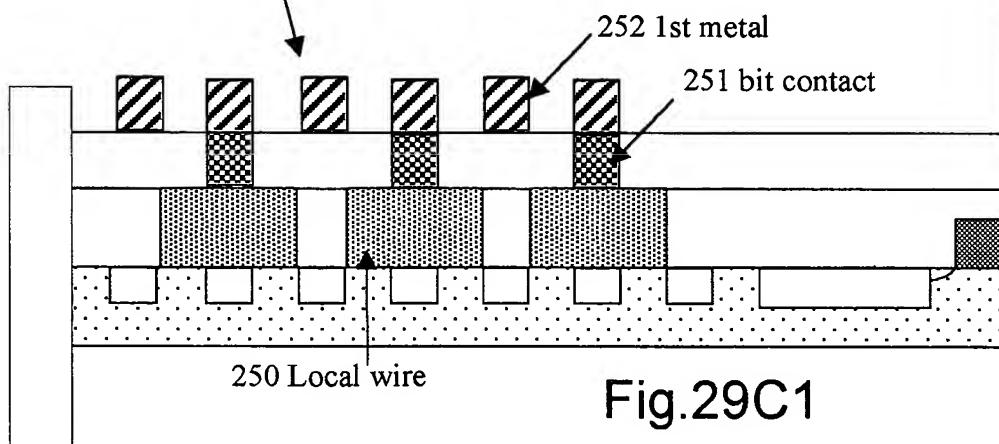
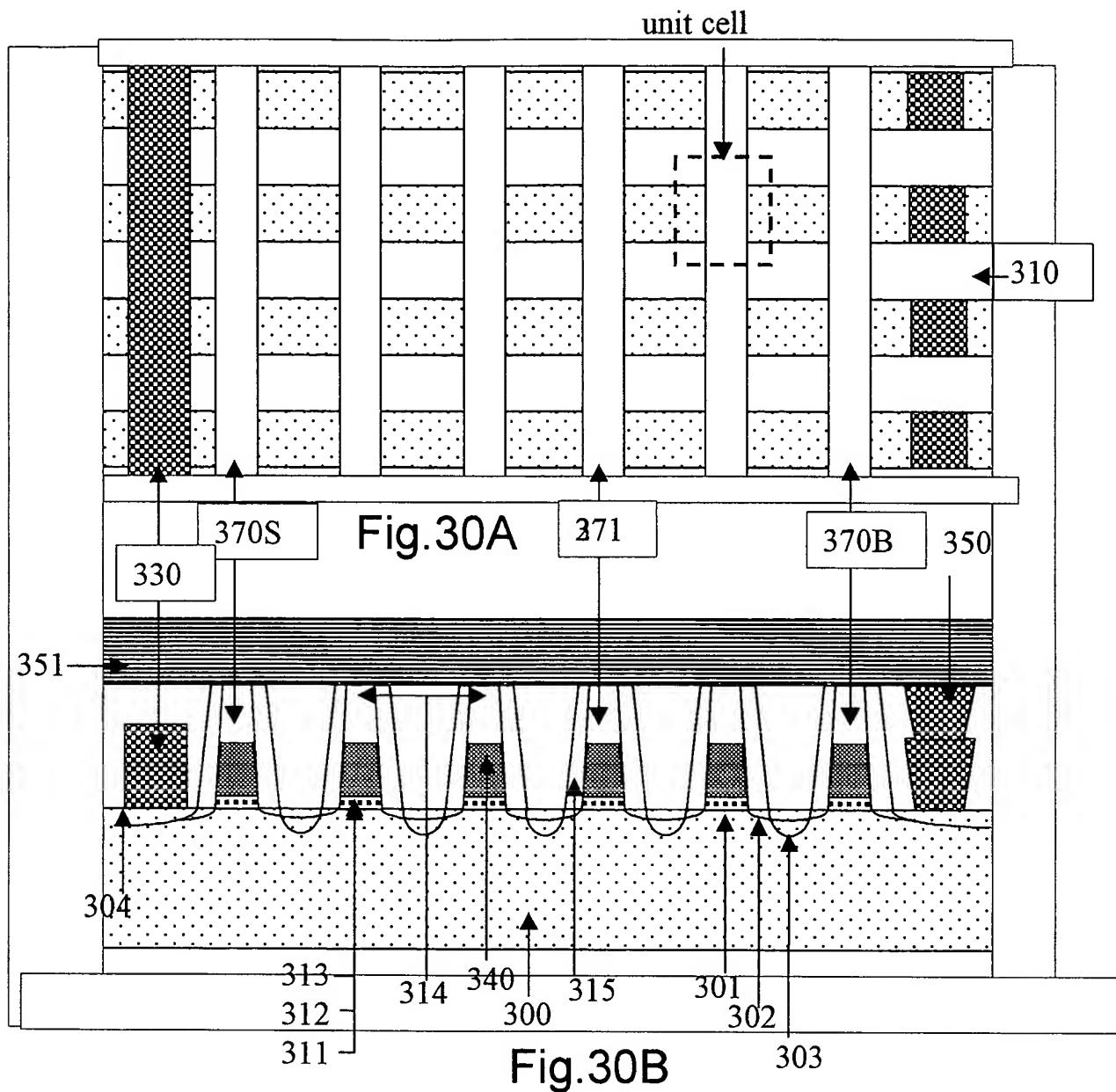


Fig.29C1



300 Substrate

310 STI

330 Local wiring

301 Control Gate Channel

311 ONO Bottom oxide

340 Control Gate Poly Si

302 Memory LDD

312 ONO Nitride

350 Bit Contact

303 Memory diffusion

313 ONO Top oxide

351 Bit Line (1st Metal)

304 Common Ground

314 CG Oxide Mask

370B Select Gate (Bit)

315 Memory Spacer

370S Select Gate (Source)

371 Control gate line

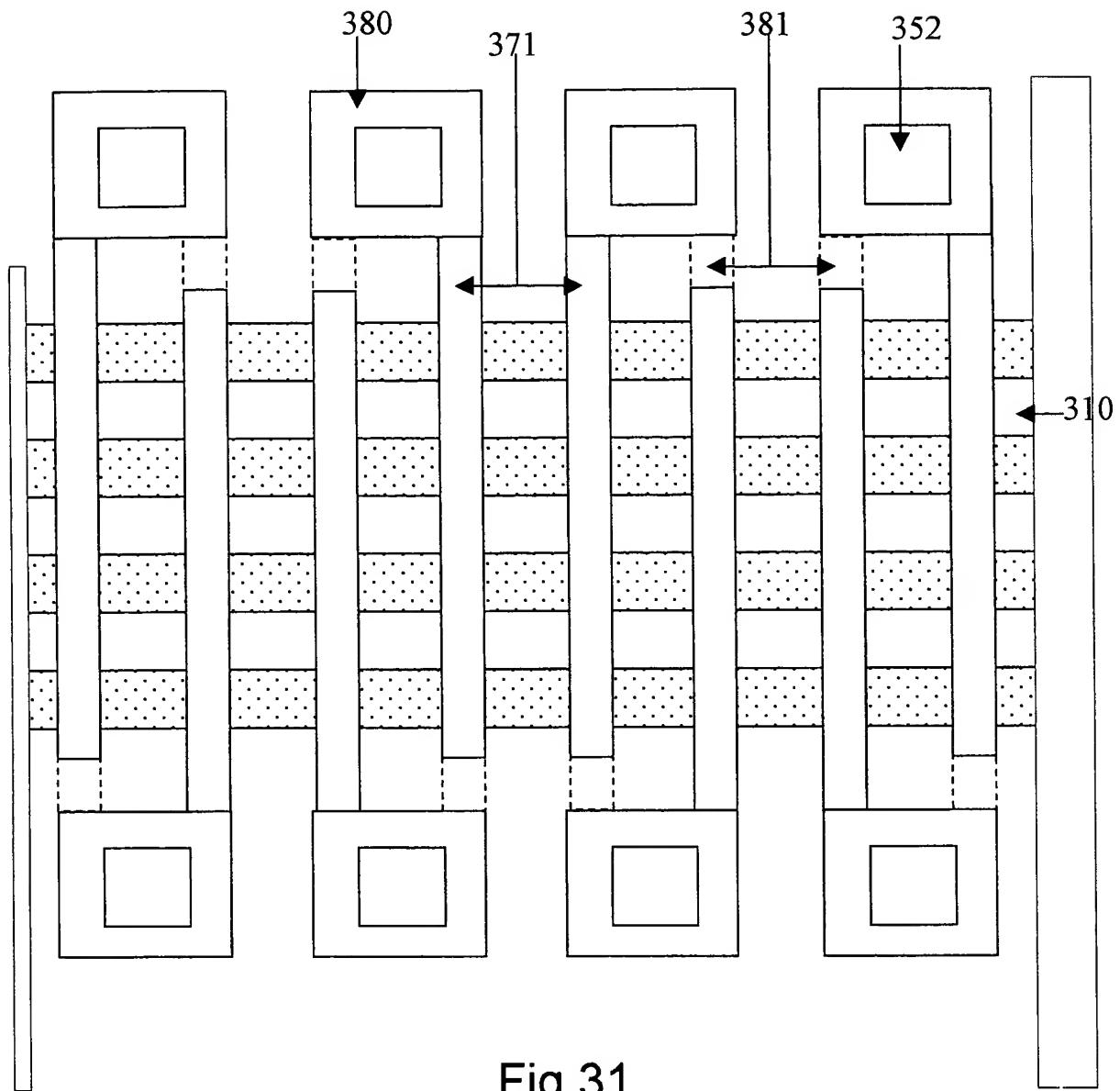


Fig.31

352 Control gate Contact

380 Control gate Contact Cover

381 Control gate Edge cut

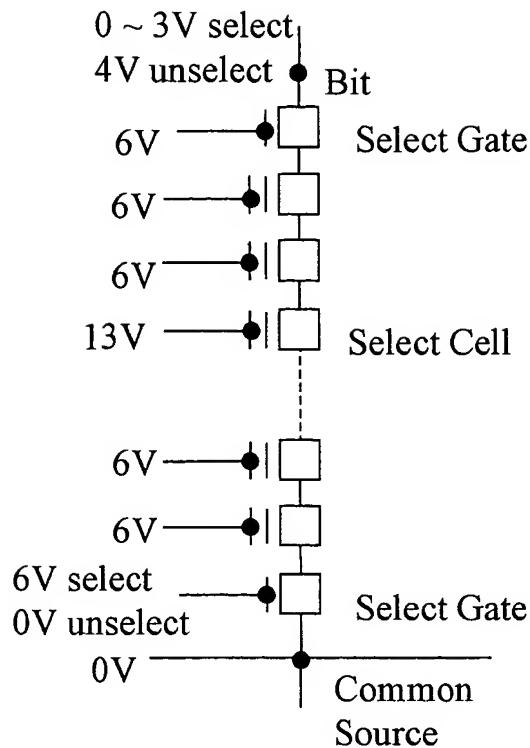


Fig.32A1

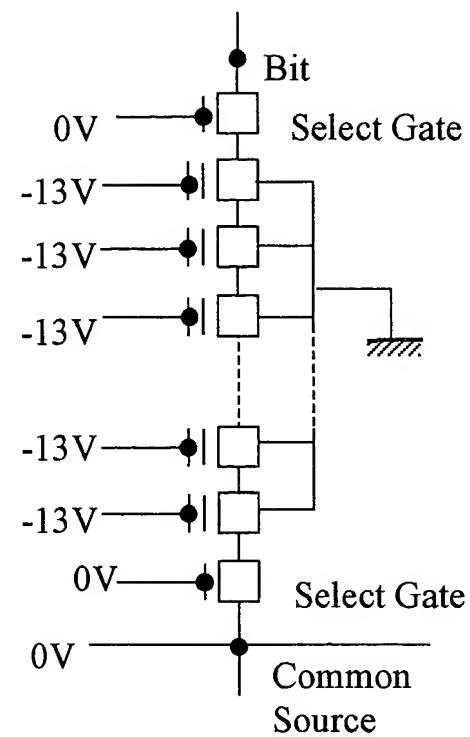


Fig.32A2

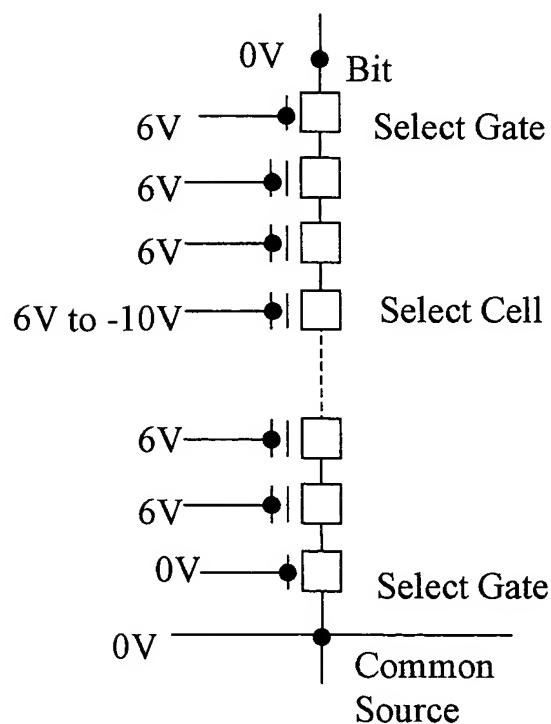


Fig.32B1

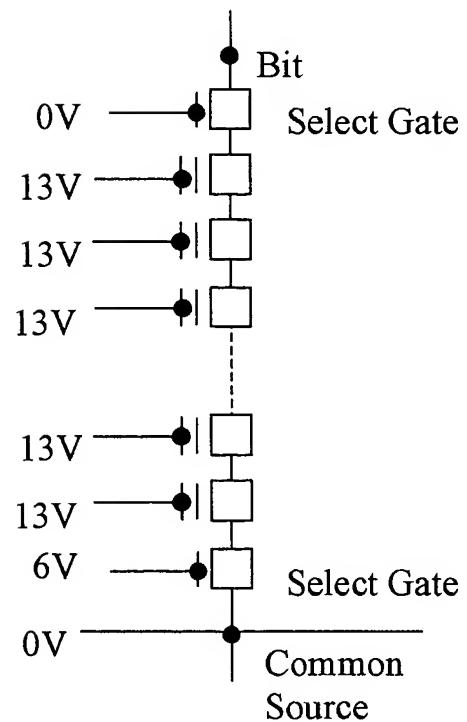
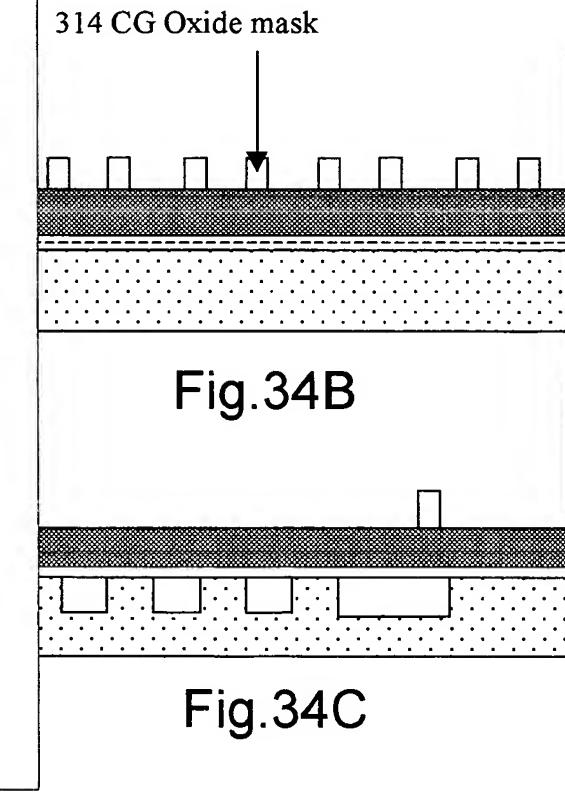
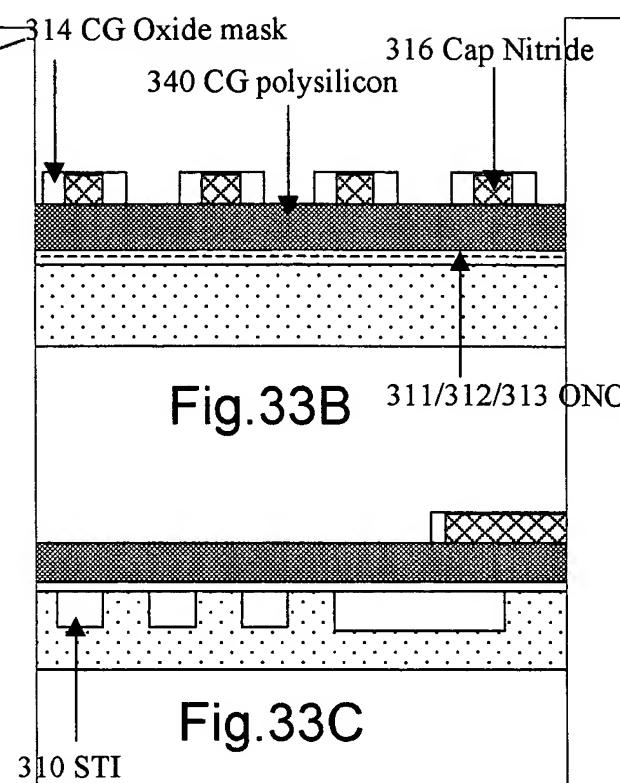
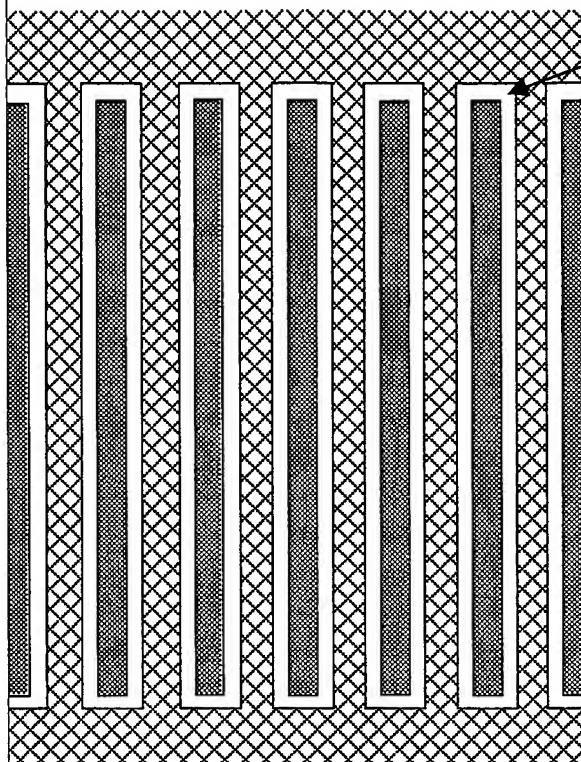
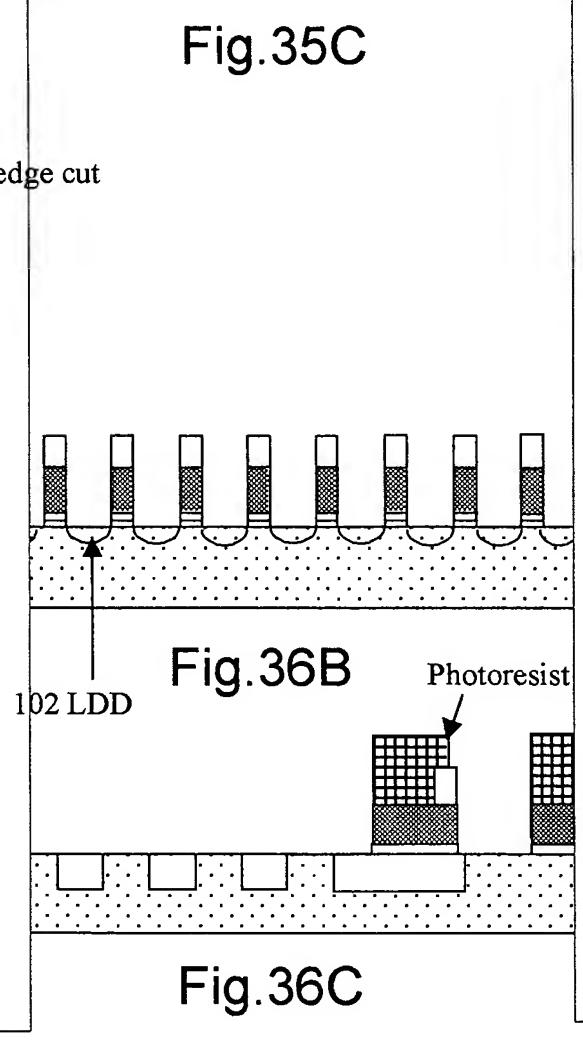
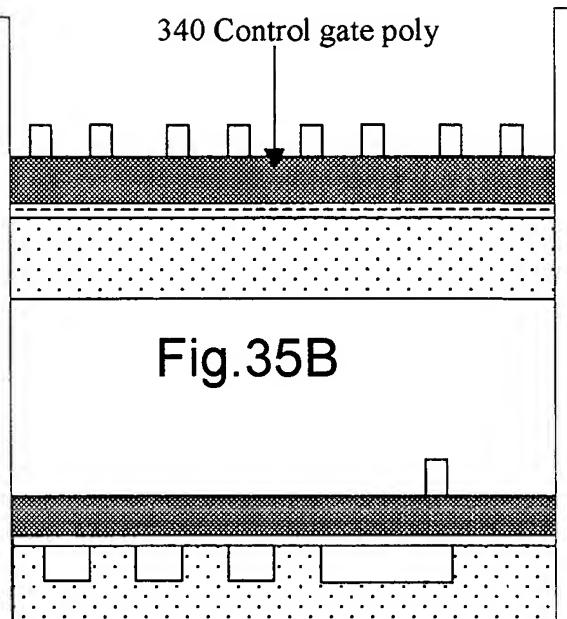
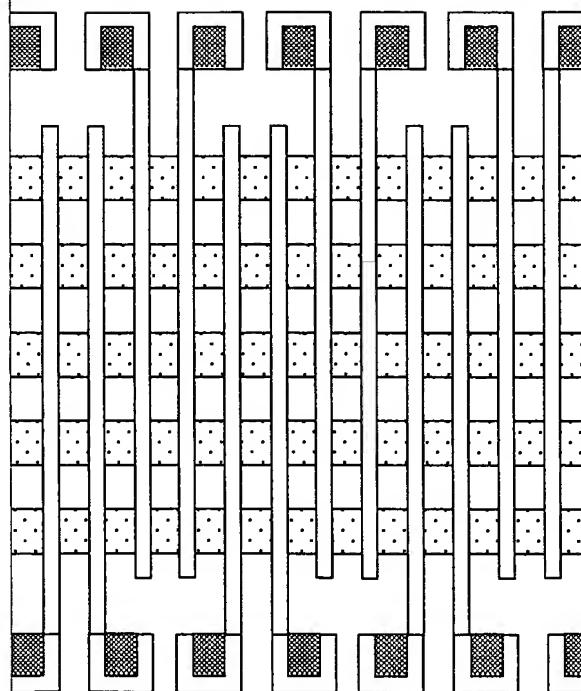
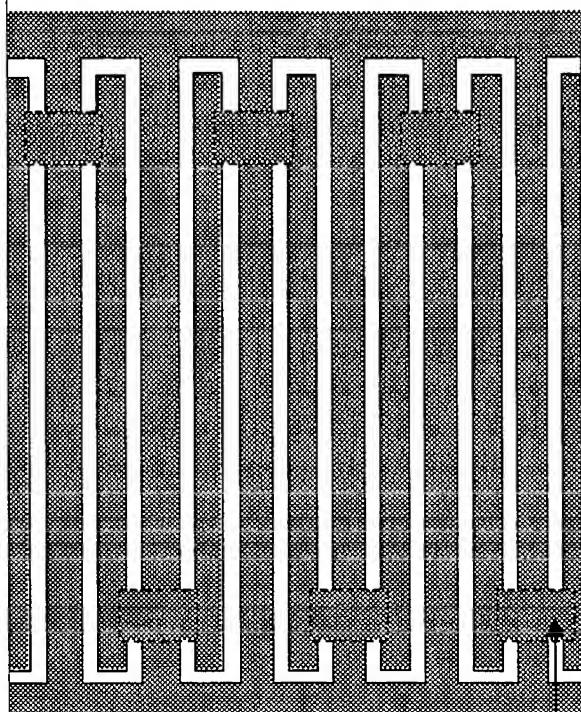
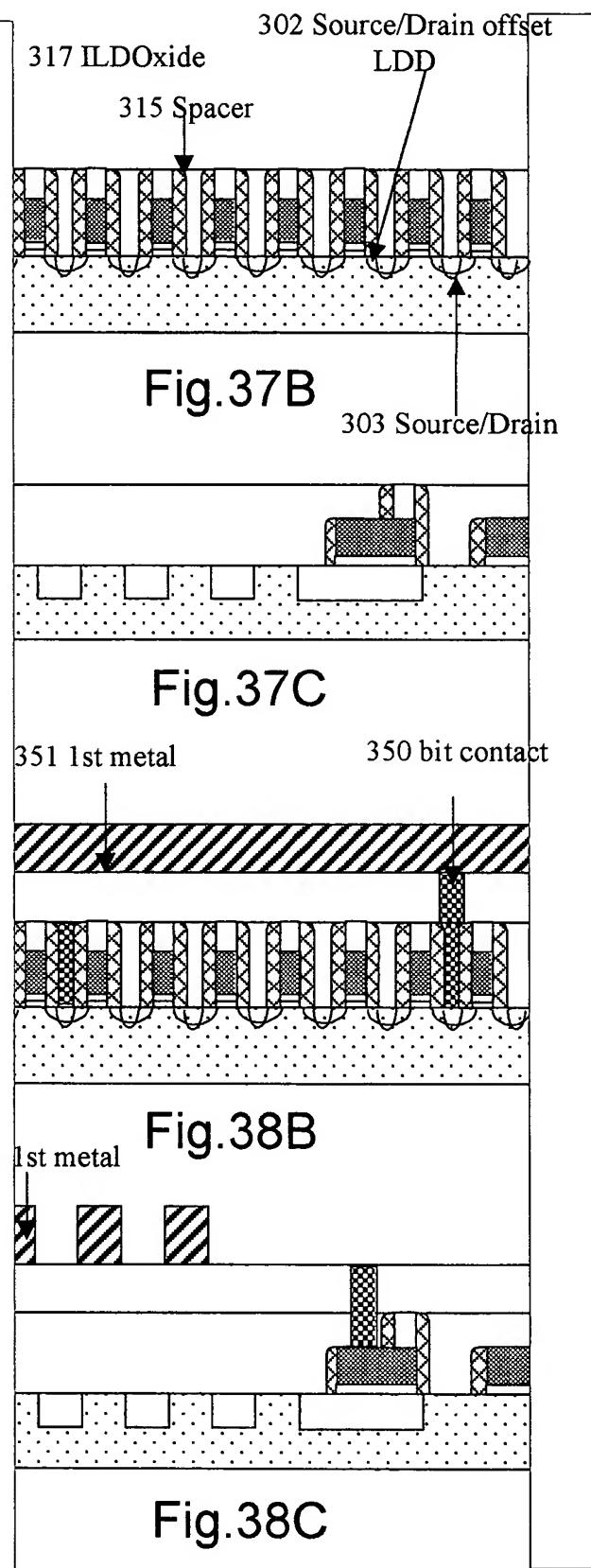
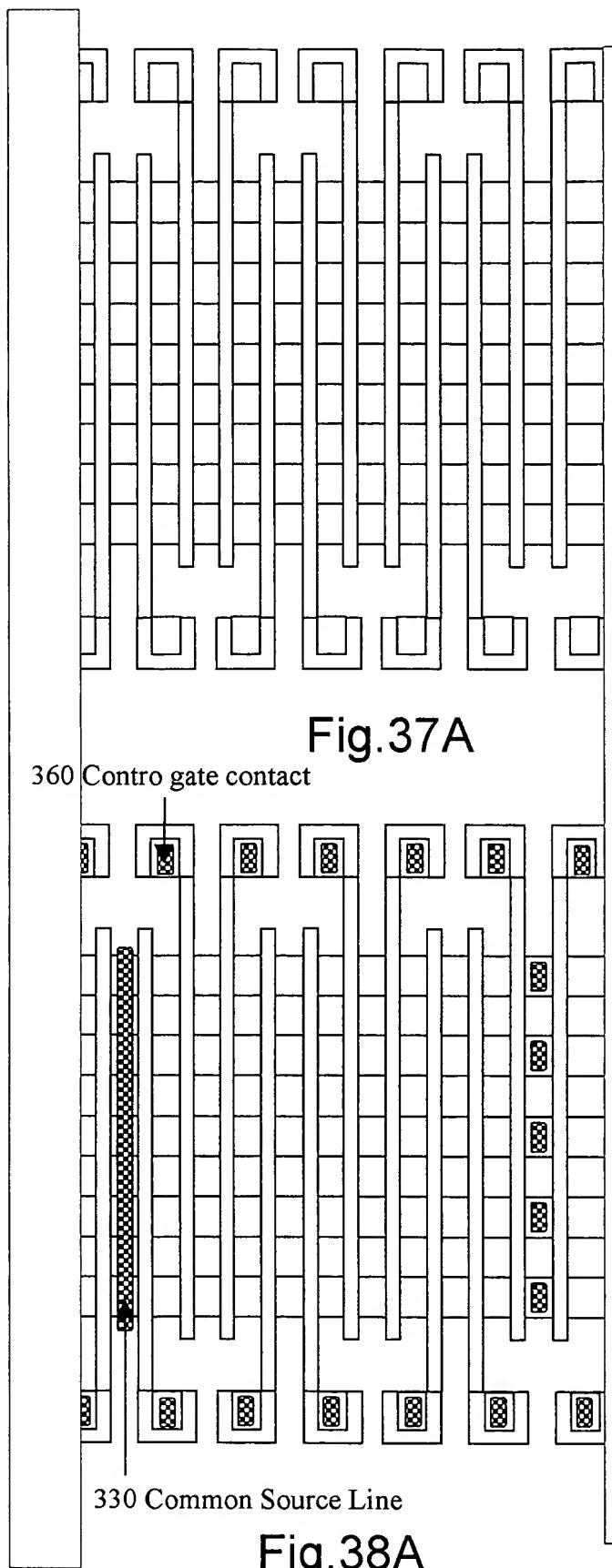


Fig.32B2







360 Contro gate contact

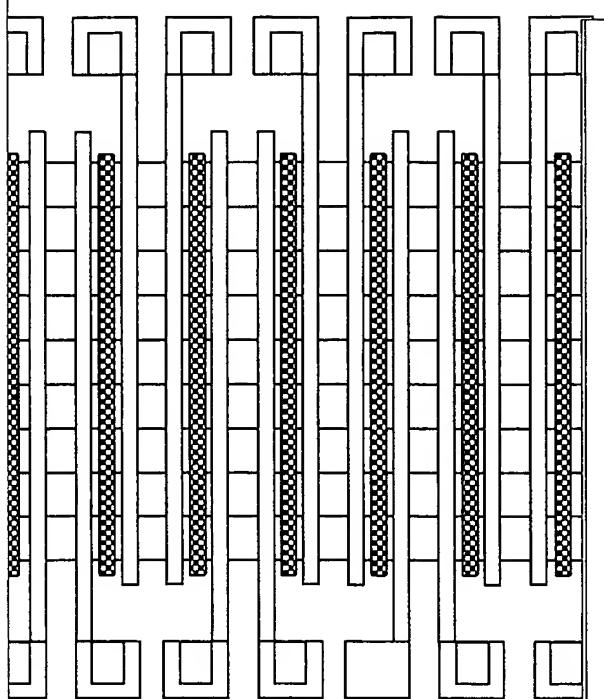


Fig.39A

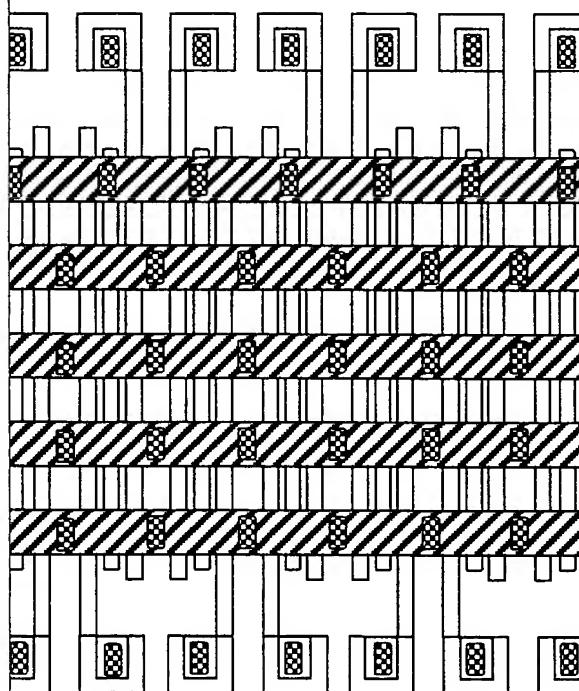


Fig.40A

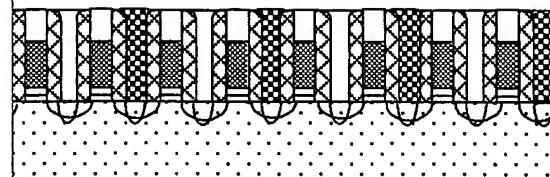


Fig.39B

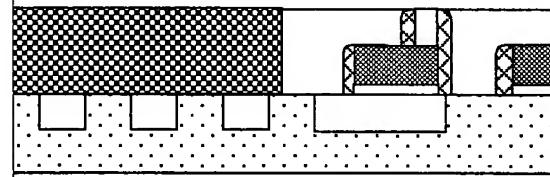


Fig.39C 319 oxide

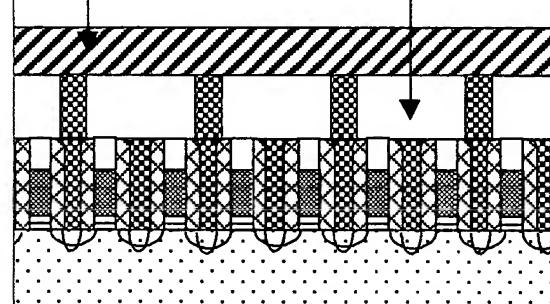


Fig.40B

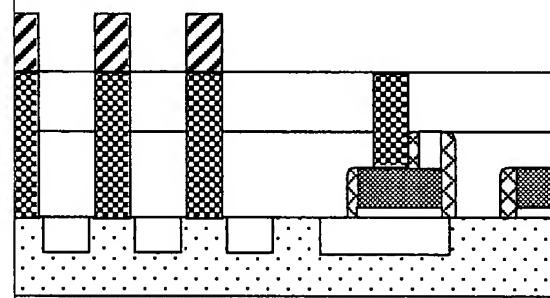
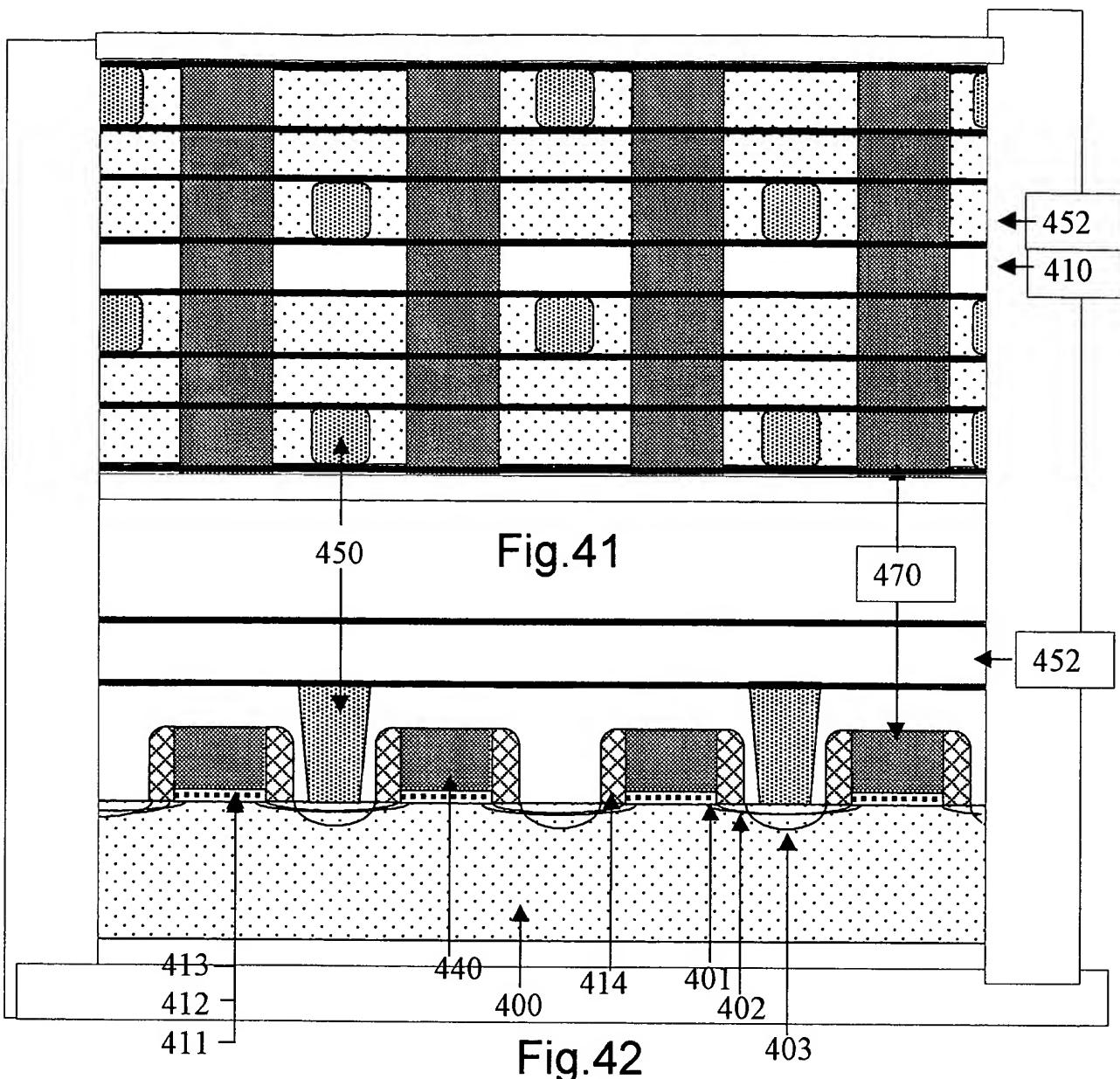


Fig.40C



400 Substrate

410 STI

440 Memory gate Si

401 Memory Halo

411 ONO Bottom oxide

450 Local wire (bit bridge)

402 Memory LDD

412 ONO Nitride

451 Bit contact

403 Memory diffusion

413 ONO Top oxide

452 Bit Line (1sr metal)

415 Memory Spacer

470 Word Line

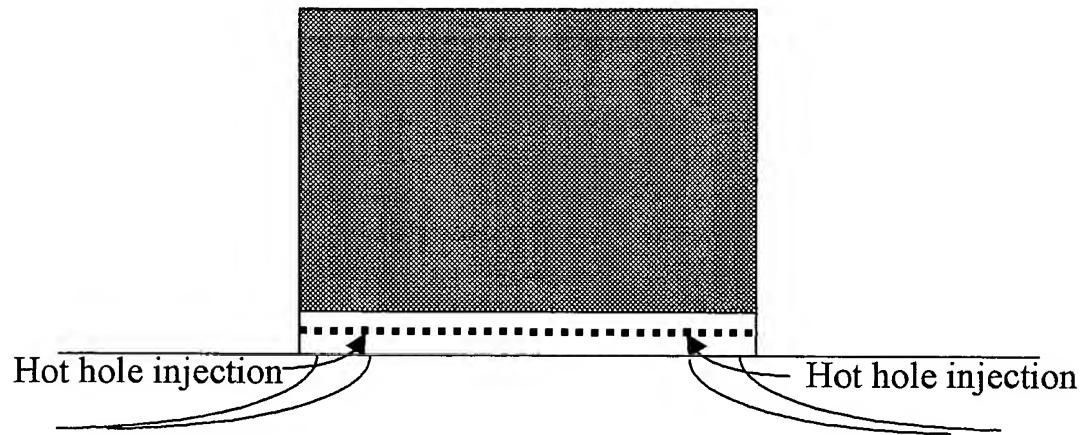


Fig.43

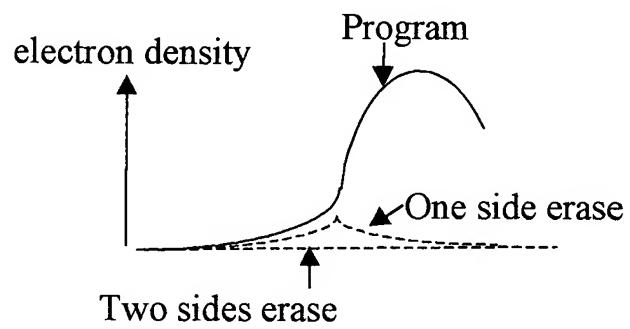


Fig.44